

100 V, Low I_Q , Synchronous Step-Down Controller for GaN FETs

FEATURES

- ▶ GaN drive technology fully optimized for GaN FETs
- ▶ Wide V_{IN} range: 4 V to 100 V
- ▶ Wide output voltage range: $0.8 V \leq V_{OUT} \leq 60 V$
- ▶ No catch, clamp, or bootstrap diodes needed
- ▶ Internal smart bootstrap switches prevent overcharging of high-side driver supplies
- ▶ Internally optimized, smart near zero dead times or resistor adjustable dead times
- ▶ Split output gate drivers for adjustable turn on and turn off driver strengths
- ▶ Accurate adjustable driver voltage and UVLO
- ▶ Low operating I_Q : 5 μA (48 V_{IN} to 5 V_{OUT})
- ▶ Programmable frequency (100 kHz to 3 MHz)
- ▶ Phase lockable frequency (100 kHz to 3 MHz)
- ▶ Spread spectrum frequency modulation
- ▶ 28-lead (4 mm x 5 mm) side wettable QFN package

APPLICATIONS

- ▶ Industrial power systems
- ▶ Military avionics and medical systems
- ▶ Telecommunications power systems

GENERAL DESCRIPTION

The LTC7891 is a high performance, step-down, dc-to-dc switching regulator controller that drives all N-channel synchronous gallium nitride (GaN) field effect transistor (FET) power stages from input voltages up to 100 V. The LTC7891 solves many of the challenges traditionally faced when using GaN FETs. The LTC7891 simplifies the application design while requiring no protection diodes and no other additional external components compared to a silicon metal-oxide semiconductor field effect transistor (MOSFET) solution.

The internal smart bootstrap switch prevents overcharging of the BOOST pin to SW pin high-side driver supplies during dead times, protecting the gate of the top GaN FET. The LTC7891 internally optimizes the gate driver timing on both switching edges to achieve smart near zero dead times, significantly improving efficiency and allowing for high frequency operation, even at high input voltages. Alternatively, the user can adjust the dead times with external resistors for margin or to tailor the application.

The gate drive voltage of the LTC7891 can be precisely adjusted from 4 V to 5.5 V to optimize performance, and to allow the use of different GaN FETs, or even logic level MOSFETs.

TYPICAL APPLICATION CIRCUIT

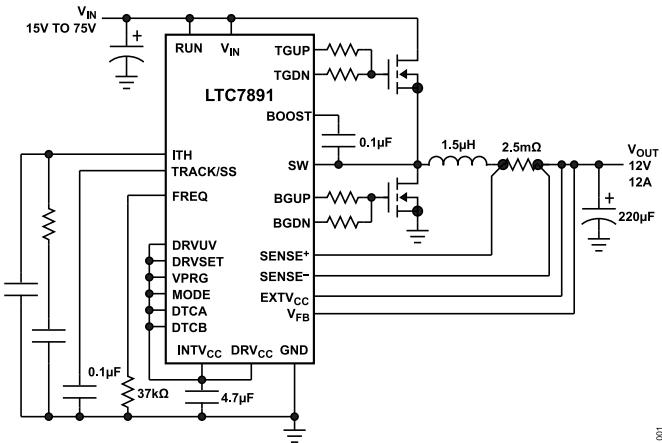


Figure 1. Typical Application Circuit

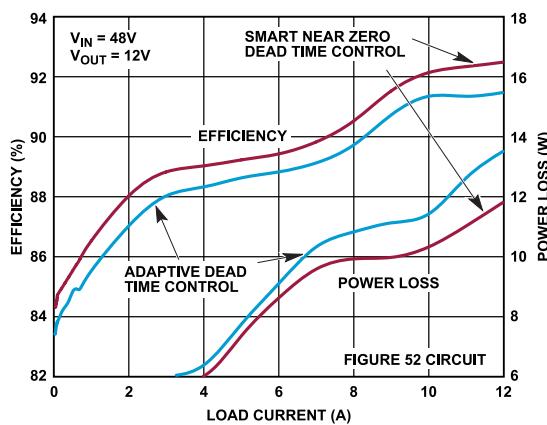


Figure 2. Efficiency and Power Loss vs. Load Current

Note that throughout this data sheet, multifunction pins, such as PLLIN/SPREAD, are referred to either by the entire pin name or by a single function of the pin, for example, PLLIN, when only that function is relevant.

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REVISION HISTORY

5/2022—Revision 0: Initial Version

SPECIFICATIONS

ELECTRICAL CHARACTERISTICS

$T_J = -40^\circ\text{C}$ to $+150^\circ\text{C}$ for the minimum and maximum values, $T_A = 25^\circ\text{C}$ for the typical values, $V_{IN} = 12\text{ V}$, $RUN = 12\text{ V}$, $VPRG = \text{floating}$, $EXTV_{CC} = 0\text{ V}$, $DRVSET = 0\text{ V}$, $DRVUV = 0\text{ V}$, $TGUP = TGDN = TG_{xx}$, $BGUP = BGDN = BG_{xx}$, and $DTCA$ and $DTCB = 0\text{ V}$, unless otherwise noted.

Table 1. Electrical Characteristics

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
INPUT SUPPLY						
Input Supply Operating Range	V_{IN}		4		100	V
Total Input Supply Current in Regulation	I_{VIN}	48 V to 5 V, no load ¹ 14 V to 3.3 V, no load ¹		5		μA
				14		μA
CONTROLLER OPERATION						
Regulated Output Voltage Set Point	V_{OUT}		0.8		60	V
Regulated Feedback Voltage ²	V_{FB}	$V_{IN} = 4\text{ V}$ to 100 V , ITH voltage = 0.6 V to 1.2 V $VPRG = \text{floating}$, $T_A = 25^\circ\text{C}$ $VPRG = \text{floating}$ $VPRG = 0\text{ V}$ $VPRG = INTV_{CC}$ $VPRG = \text{floating}$, $T_A = 25^\circ\text{C}$ $VPRG = 0\text{ V}$ or $INTV_{CC}$, $T_A = 25^\circ\text{C}$ Relative to V_{FB} , $T_A = 25^\circ\text{C}$	0.792	0.8	0.808	V
Feedback Current ²		$V_{FB} = 4\text{ V}$ to 100 V , ITH voltage = 0.6 V to 1.2 V $VPRG = \text{floating}$, $T_A = 25^\circ\text{C}$ $VPRG = 0\text{ V}$ or $INTV_{CC}$, $T_A = 25^\circ\text{C}$ Relative to V_{FB} , $T_A = 25^\circ\text{C}$	0.788	0.8	0.812	V
Feedback Overvoltage Threshold			4.925	5.0	5.075	V
Transconductance Amplifier ²	g_M	$V_{FB} = 4\text{ V}$ to 100 V , ITH voltage = 0.6 V to 1.2 V	11.82	12	12.18	V
Maximum Current Sense Threshold	$V_{SENSE(MAX)}$	$V_{FB} = 0.7\text{ V}$, $SENSE^- = 3.3\text{ V}$ $ILIM = 0\text{ V}$ $ILIM = \text{floating}$ $ILIM = INTV_{CC}$	-50	0	+50	nA
$SENSE^+$ Pin Current	I_{SENSE^+}	$SENSE^+ = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$	21	26	31	mV
$SENSE^-$ Pin Current	I_{SENSE^-}	$SENSE^- < 3\text{ V}$ $3.2\text{ V} \leq SENSE^- < INTV_{CC} - 0.5\text{ V}$ $SENSE^- > INTV_{CC} + 0.5\text{ V}$	45	50	55	mV
Soft Start Charge Current		$SENSE^+ = 3.3\text{ V}$, $T_A = 25^\circ\text{C}$	67	75	83	mV
RUN Pin On Threshold		$SENSE^- < 3\text{ V}$	-1		+1	μA
RUN Pin Hysteresis		$3.2\text{ V} \leq SENSE^- < INTV_{CC} - 0.5\text{ V}$	1			μA
DC SUPPLY CURRENT						
V_{IN} Shutdown Current		$SENSE^- > INTV_{CC} + 0.5\text{ V}$	75			μA
V_{IN} Sleep Mode Current		$SENSE^- > INTV_{CC} + 0.5\text{ V}$	725			μA
Sleep Mode Current ³		$SENSE^- > INTV_{CC} + 0.5\text{ V}$	9.5	12	14.5	μA
		$SENSE^- > INTV_{CC} + 0.5\text{ V}$	1.15	1.20	1.25	V
Pulse Skipping (PS) or Forced Continuous Mode (FCM), V_{IN} or $EXTV_{CC}$ Current ³		$SENSE^- > INTV_{CC} + 0.5\text{ V}$	120			mV

SPECIFICATIONS

Table 1. Electrical Characteristics

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
GATE DRIVERS						
TGxx or BGxx On-Resistance		DRVSET = INTV _{CC}				
Pull-Up			2.0			Ω
Pull-Down			1.0			Ω
BOOST to DRV _{CC} Switch On-Resistance		DRVSET = INTV _{CC}		7		Ω
TGxx or BGxx Transition Time ⁴						
Rise Time			25			ns
Fall Time			15			ns
TGxx Off to BGxx On Delay ⁴						
Synchronous Switch On Delay Time		DTCA = 0 V		20		ns
BGxx Off to TGxx On Delay ⁴						
Top Switch On Delay Time		DTCB = 0 V		20		ns
BGxx Falling to SW Rising Delay ⁵		DTCA = INTV _{CC} , DTCB = INTV _{CC} or resistor		2		ns
		DTCA = 50 kΩ, DTCB = INTV _{CC} or resistor		25		ns
		DTCA = 100 kΩ, DTCB = INTV _{CC} or resistor		40		ns
SW Falling to BGxx Rising Delay ⁵		DTCA = INTV _{CC} , DTCA = INTV _{CC} or resistor		0.5		ns
		DTCB = 50 kΩ, DTCA = INTV _{CC} or resistor		25		ns
		DTCB = 100 kΩ, DTCA = INTV _{CC} or resistor		40		ns
TGxx Minimum On-Time ⁶	t _{ON(MIN)}			40		ns
Maximum Duty Cycle		Output in dropout, FREQ = 0 V		99		%
INTV _{CC} LOW DROPOUT (LDO)						
LINEAR REGULATORS						
INTV _{CC} Voltage for V _{IN} and EXTV _{CC} LDOs		EXTV _{CC} = 0 V for V _{IN} LDO, 12 V for EXTV _{CC} LDO				
		DRVSET = INTV _{CC}	5.2	5.5	5.7	V
		DRVSET = 0 V	4.8	5.0	5.2	V
		DRVSET = 64.9 kΩ	4.5	4.75	5.0	V
DRV _{CC} Load Regulation		DRV _{CC} load current (I _{CC}) = 0 mA to 100 mA, T _A = 25°C		1	3	%
Undervoltage Lockout	UVLO					
DRV _{CC} Rising		DRVUV = INTV _{CC}	4.8	5.0	5.2	V
		DRVUV = 0 V	3.6	3.8	4.0	V
		DRVUV = floating	4.2	4.4	4.6	V
DRV _{CC} Falling		DRVUV = INTV _{CC}	4.55	4.75	4.95	V
		DRVUV = 0 V	3.4	3.6	3.8	V
		DRVUV = floating	4.0	4.18	4.4	V
EXTV _{CC} LDO Switchover Voltage						
EXTV _{CC} Rising		DRVUV = INTV _{CC} or floating, T _A = 25°C	5.75	5.95	6.15	V
		DRVUV = 0 V, T _A = 25°C	4.6	4.76	4.9	V
EXTV _{CC} Switchover Hysteresis						
EXTV _{CC} Falling		DRVUV = INTV _{CC} or floating		390		mV
		DRVUV = 0 V		220		mV

SPECIFICATIONS

Table 1. Electrical Characteristics

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
SPREAD SPECTRUM OSCILLATOR AND PHASE-LOCKED LOOP						
Fixed Frequency	f_{osc}	PLLIN/SPREAD = 0 V				
Low Fixed Frequency		FREQ voltage (V_{FREQ}) = 0 V, $T_A = 25^\circ C$	320	370	420	kHz
High Fixed Frequency		$V_{FREQ} = INTV_{CC}$	2.0	2.25	2.5	MHz
Programmable Frequency		$FREQ = 374 \text{ k}\Omega$		100		kHz
		$FREQ = 75 \text{ k}\Omega, T_A = 25^\circ C$	450	500	550	kHz
		$FREQ = 12.5 \text{ k}\Omega$		3		MHz
Synchronizable Frequency Range	f_{sync}	PLLIN/SPREAD = external clock	0.1	3		MHz
PLLIN Input High Level			2.2			V
PLLIN Input Low Level					0.5	V
Spread Spectrum Frequency Range (Relative to f_{osc})		PLLIN/SPREAD = $INTV_{CC}$				
Minimum Frequency				0		%
Maximum Frequency				20		%
PGOOD OUTPUT						
PGOOD Voltage Low		PGOOD current (I_{PGOOD}) = 2 mA, $T_A = 25^\circ C$		0.2	0.4	V
PGOOD Leakage Current		$PGOOD = 5 \text{ V}$			± 1	μA
PGOOD Trip Level		V_{FB} rising, $T_A = 25^\circ C$	7	10	13	%
V_{FB} with Respect to Set Regulated Voltage		Hysteresis		1.6		%
		V_{FB} falling, $T_A = 25^\circ C$	-13	-10	-7	%
		Hysteresis		1.6		%
PGOOD Delay for Reporting a Fault				25		μs

¹ This specification is not tested in production.

² The LTC7891 is tested in a feedback loop that servos V_{ITH} to a specified voltage and measures the resultant V_{FB} .

³ SENSE⁻ bias current is reflected to the input supply by the formula $I_{VIN} = I_{SENSE^-} \times V_{OUT}/(V_{IN} \times \eta)$, where η is the efficiency.

⁴ Rise and fall times are measured using 10% and 90% levels. Delay times are measured using 50% levels.

⁵ SW falling to BGxx rising and BGxx falling to SW rising delay times are measured at the rising and falling thresholds on SW and BGxx of approximately 1 V. See Figure 41 and Figure 42.

⁶ The minimum on-time condition specified for inductor peak-to-peak ripple current is >40% of the maximum load current (I_{MAX}) (see the Minimum On Time Considerations section).

ABSOLUTE MAXIMUM RATINGS

Table 2. Absolute Maximum Ratings

Parameter	Rating
Input Supply (V_{IN})	-0.3 V to +100 V
RUN	-0.3 V to +100 V
BOOST	-0.3 V to +106 V
SW	-5 V to +100 V
BOOST to SW	-0.3 V to +6 V
BGUP, BGDN, TGUP, TGDN ¹	Not applicable
EXTV _{CC}	-0.3 V to +30 V
DRV _{CC} , INTV _{CC} , BSTV _{CC}	-0.3 V to +6 V
V_{FB}	-0.3 V to +15 V
PLLIN/SPREAD, FREQ	-0.3 V to +6 V
TRACK/SS, ITH	-0.3 V to +6 V
DRVSET, DRUV	-0.3 V to +6 V
MODE, ILIM, VPRG	-0.3 V to +6 V
PGOOD	-0.3 V to +6 V
DTCA, DTCB	-0.3 V to +6 V
SENSE ⁺ , SENSE ⁻	-0.3 V to +65 V
SENSE ⁺ to SENSE ⁻	
Continuous	-0.3 V to +0.3 V
<1 ms	-100 mA to +100 mA
Operating Junction Temperature Range ²	-40°C to +150°C
Storage Temperature Range	-65°C to +150°C

¹ Do not apply a voltage or current source to these pins. They must be connected to capacitive loads only. Otherwise, permanent damage may occur.

² The LTC7891R is specified over the -40°C to 150°C operating junction temperature range. High junction temperatures degrade operating lifetimes. Note the maximum ambient temperature consistent with these specifications is determined by specific operating conditions in conjunction with the board layout, rated package thermal impedance, and other environmental factors. The junction temperature (T_J , in °C) is calculated from the ambient temperature (T_A , in °C) and power dissipation (P_D , in Watts) according to the following formula: $T_J = T_A + (P_D \times \theta_{JA})$, where θ_{JA} (in °C/W) is the package thermal impedance.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

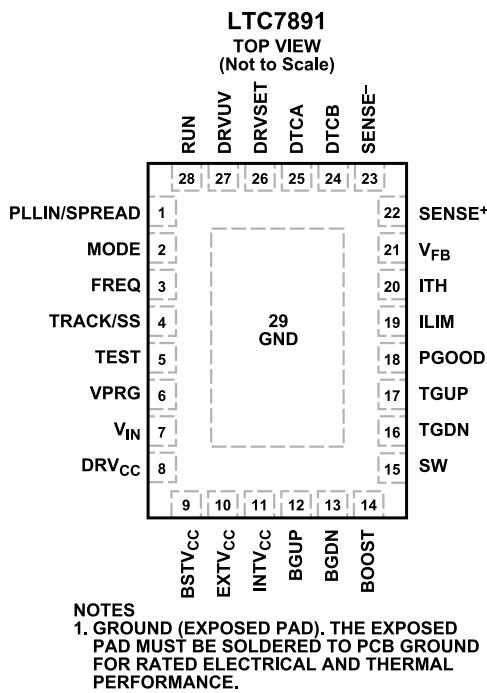


Figure 3. Pin Configuration

Table 3. Pin Function Descriptions

Pin No.	Mnemonic	Description
1	PLLIN/SPREAD	External Synchronization Input to Phase Detector/Spread Spectrum Enable. When an external clock is applied to PLLIN/SPREAD, the phase-locked loop forces the rising TGxx signal to synchronize with the rising edge of the external clock. When not synchronizing to an external clock, tie this input to INTV _{CC} to enable spread spectrum dithering of the oscillator, or to GND to disable spread spectrum dithering.
2	MODE	Mode Select Input. This input determines how the LTC7891 operates at light loads. Connect MODE to GND to select the Burst Mode operation. An internal 100 kΩ resistor to GND also invokes Burst Mode operation when MODE is floating. Connect MODE to INTV _{CC} to force continuous inductor current operation. Tying MODE to INTV _{CC} through a 100 kΩ resistor selects the pulse skipping operation.
3	FREQ	Frequency Control Pin for the Internal Voltage Controlled Oscillator (VCO). Connect FREQ to GND for a fixed frequency of 370 kHz. Connect FREQ to INTV _{CC} for a fixed frequency of 2.25 MHz. Program frequencies between 100 kHz and 3 MHz by using a resistor between FREQ and GND. Minimize the capacitance on FREQ.
4	TRACK/SS	External Tracking/Soft Start Input. TRACK/SS regulates the V _{FB} voltage to the lesser of 0.8 V or the voltage on the TRACK/SS pin. An internal 12 μA pull-up current source is connected to TRACK/SS. A capacitor to GND at TRACK/SS sets the ramp time to the final regulated output voltage. The ramp time is equal to 1 ms for every 12.5 nF of capacitance. Alternatively, a resistor divider on another voltage supply connected to TRACK/SS allows the output to track the other supply during startup.
5	TEST	Test Pin. This pin must be soldered to PCB GND.
6	VPRG	Output Voltage Control Pin. VPRG sets the adjustable output mode using external feedback resistors or the fixed 12 V or 5 V output mode. Floating VPRG programs the output from 0.8 V to 60 V with an external resistor divider, regulating V _{FB} to 0.8 V. Connect VPRG to INTV _{CC} or GND to program the output to 12 V or 5 V, respectively, through an internal resistor divider on V _{FB} .
7	V _{IN}	Main Supply Pin. A bypass capacitor must be tied between V _{IN} and GND.
8	DRV _{CC}	Gate Driver Power Supply Pin. The gate drivers are powered from DRV _{CC} . Connect DRV _{CC} to INTV _{CC} by a separate trace to the INTV _{CC} bypass capacitor.
9	BST _{CC}	Bootstrap Diode Anode Connection Pin. Place an optional external Schottky diode between the BST _{CC} and BOOST pins to bypass most of the 7 Ω switch resistance between DRV _{CC} and BOOST.
10	EXTV _{CC}	External Power Input to an Internal LDO Regulator Connected to DRV _{CC} . This LDO regulator supplies INTV _{CC} power, bypassing the internal V _{IN} LDO regulator whenever EXTV _{CC} is higher than the EXTV _{CC} switchover voltage. See the EXTV _{CC} connection in the Power and Bias Supplies (VIN, EXTV_{CC}, DRV_{CC}, and INTV_{CC}) section and INTV_{CC} Regulators (OPTI-DRIVE) section. Do not exceed 30 V on EXTV _{CC} . Connect EXTV _{CC} to GND if the EXTV _{CC} LDO regulator is not used.
11	INTV _{CC}	Output of the Internal LDO Regulator. The INTV _{CC} voltage regulation point is set by the DRVSET pin. INTV _{CC} must be decoupled to GND with a 4.7 μF to 10 μF ceramic or other low equivalent series resistance (ESR) capacitor.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

Table 3. Pin Function Descriptions

Pin No.	Mnemonic	Description
12	BGUP	High Current Gate Driver Pull-Up for Bottom FET. BGUP pulls up to DRV_{CC} . Tie BGUP directly to the bottom FET gate for maximum gate drive transition speed on the gate rising edge. Tie a resistor between BGUP and the bottom FET gate to adjust the gate rising slew rate. BGUP also serves as the Kelvin sense of the bottom FET gate during turn off.
13	BGDN	High Current Gate Driver Pull-Down for Bottom FET. BGDN pulls down to GND. Tie BGDN directly to the bottom FET gate for maximum gate drive transition speed on the gate falling edge. Tie a resistor between BGDN and the bottom FET gate to adjust the gate falling slew rate. BGDN also serves as the Kelvin sense of the bottom FET gate during turn on.
14	BOOST	Bootstrapped Supply to the Top Side Floating Driver. Connect a capacitor between the BOOST and SW pins. An internal switch provides power to the BOOST pin from DRV_{CC} when the bottom FET turns on. The voltage swing at the BOOST pin is from DRV_{CC} to ($V_{IN} + DRV_{CC}$).
15	SW	Switch Node Connection to Inductor.
16	TGDN	High Current Gate Driver Pull-Down for Top FET. TGDN pulls down to SW. Tie TGDN directly to the top FET gate for maximum gate drive transition speed on the gate falling edge. Tie a resistor between TGDN and the top FET gate to adjust the gate falling slew rate.
17	TGUP	High Current Gate Driver Pull-Up for Top FET. TGUP pulls up to BOOST. Tie TGUP directly to the top FET gate for maximum gate drive transition speed on the gate rising edge. Tie a resistor between TGUP and the top FET gate to adjust the gate rising slew rate.
18	PGOOD	Power Good Open-Drain Logic Output. PGOOD is pulled to GND when the voltage on V_{FB} is not within $\pm 10\%$ of its set point.
19	ILIM	Current Comparator Sense Voltage Range Input. Tying ILIM to GND or $INTV_{CC}$ or floating ILIM sets the maximum current sense threshold to one three different levels (25 mV, 75 mV, and 50 mV, respectively).
20	ITH	Error Amplifier Output and Switching Regulator Compensation Point. The current comparator trip point increases with this control voltage.
21	V_{FB}	Error Amplifier Feedback Input. If VPRG is floating, V_{FB} receives the remotely sensed feedback voltage from an external resistive divider across the output. If VPRG is tied to GND or $INTV_{CC}$, V_{FB} receives the remotely sensed output voltage directly.
22	SENSE ⁺	The Positive Input to the Differential Current Comparator. The ITH pin voltage and controlled offset between the SENSE ⁻ and SENSE ⁺ pins, in conjunction with the current sense resistor (R_{SENSE}), set the current trip threshold.
23	SENSE ⁻	The Negative Input to the Differential Current Comparator. The SENSE ⁻ pin supplies current to the current comparator when SENSE ⁻ is greater than $INTV_{CC}$. When SENSE ⁻ is 3.2 V or greater, the pin supplies the majority of the sleep mode quiescent current instead of V_{IN} , further reducing the input referred quiescent current.
24	DTCB	Dead Time Control Pin for Top FET Off to Bottom FET On Delay. Connect DTCB to GND to program an adaptive dead time delay of approximately 20 ns. Connect DTCB to $INTV_{CC}$ to program a smart near zero delay between SW falling and BGDN rising. Connect a 10 k Ω to 200 k Ω resistor between DTCB and GND to add additional delay (from 7 ns to 60 ns) between SW falling and BGDN rising.
25	DTCA	Dead Time Control Pin for Bottom FET Off to Top FET On Delay. Connect DTCA to GND to program an adaptive dead time delay of approximately 20 ns. Connect DTCA to $INTV_{CC}$ to program a smart near zero delay between BGUP falling and SW rising. Connect a 10 k Ω to 200 k Ω resistor between DTCA and GND to add additional delay (from 7 ns to 60 ns) between BGUP falling and SW rising.
26	DRVSET	$INTV_{CC}$ Regulation Program Pin. DRVSET sets the regulation point for the $INTV_{CC}$ LDO linear regulators. Connect DRVSET to GND to set $INTV_{CC}$ to 5 V. Connect DRVSET to $INTV_{CC}$ to set $INTV_{CC}$ to 5.5 V. Program voltages between 4 V and 5.5 V by placing a resistor (50 k Ω to 110 k Ω) between DRVSET and GND. The resistor and an internal 20 μ A source current create a voltage used by the $INTV_{CC}$ LDO regulator to set the regulation point.
27	DRVUV	DRV_{CC} UVLO and $EXTV_{CC}$ Switchover Program Pin. DRVUV determines the $INTV_{CC}$ UVLO and $EXTV_{CC}$ switchover rising and falling thresholds, as listed in Table 1.
28	RUN	Run Control Input for the Controller. Forcing RUN below 1.08 V disables controller switching. Forcing RUN below 0.7 V shuts down the LTC7891, reducing quiescent current to approximately 1 μ A. Tie the RUN pin to V_{IN} for always on operation.
29	GND (EPAD)	Ground (Exposed Pad). The exposed pad must be soldered to PCB GND for rated electrical and thermal performance.

TYPICAL PERFORMANCE CHARACTERISTICS

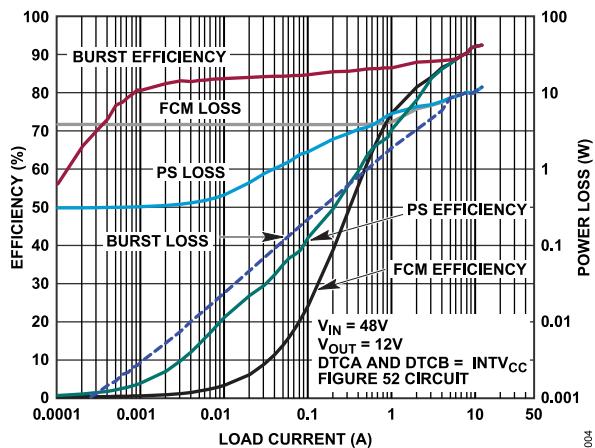


Figure 4. Efficiency and Power Loss vs. Load Current

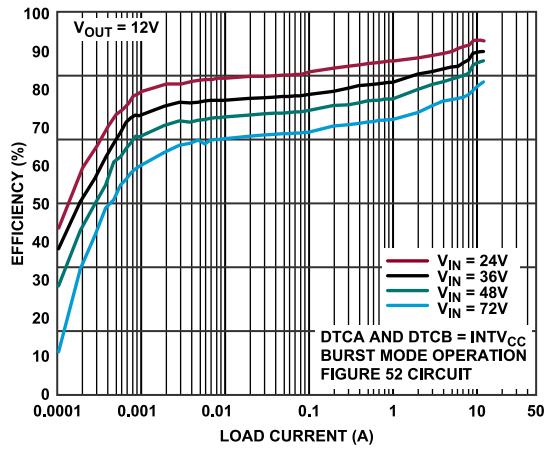


Figure 5. Efficiency vs. Load Current

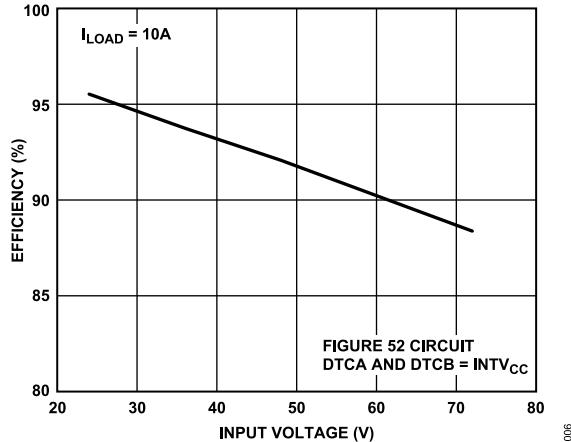
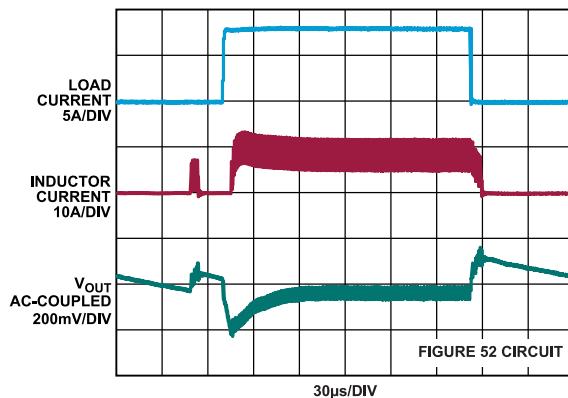
Figure 6. Efficiency vs. Input Voltage (I_{LOAD} Is Load Current)

Figure 7. Load Step Burst Mode Operation

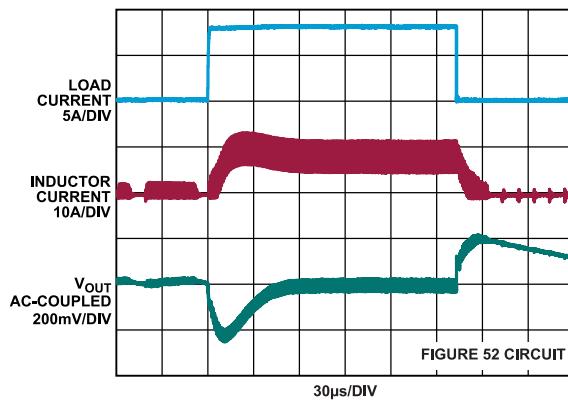


Figure 8. Load Step Pulse Skipping Mode

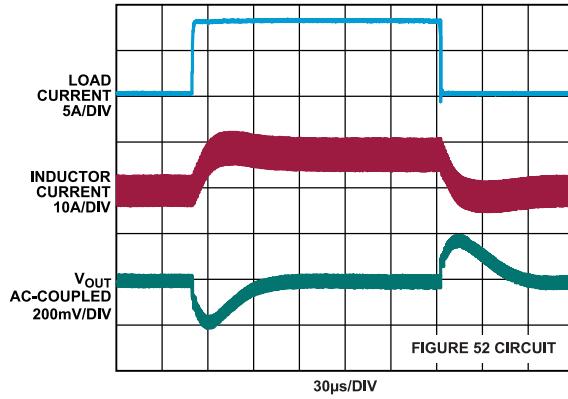


Figure 9. Load Step Forced Continuous Mode

TYPICAL PERFORMANCE CHARACTERISTICS

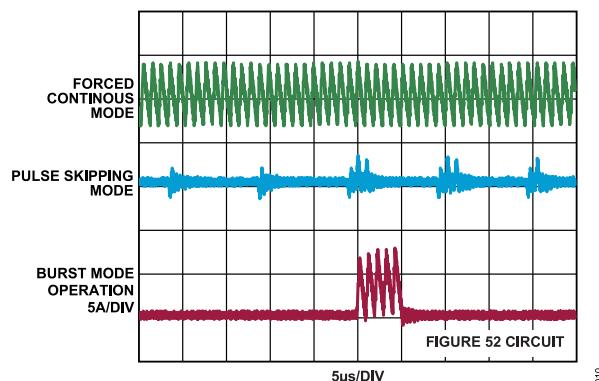


Figure 10. Inductor Current at Light Load

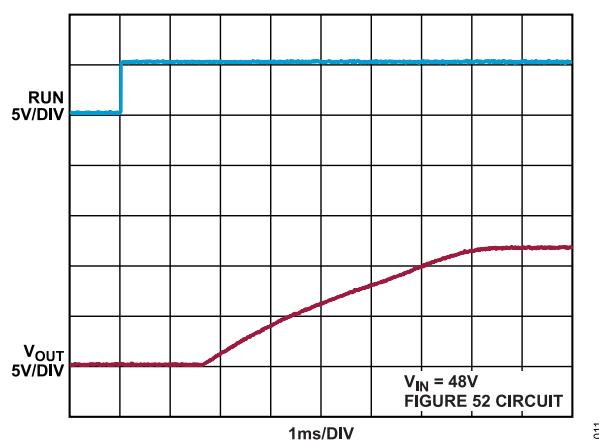


Figure 11. Soft Startup

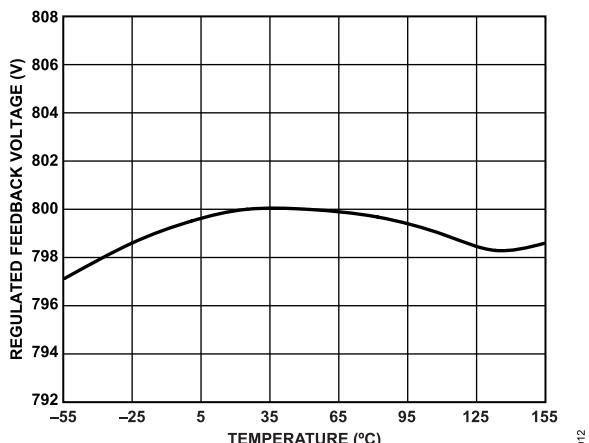


Figure 12. Regulated Feedback Voltage vs. Temperature

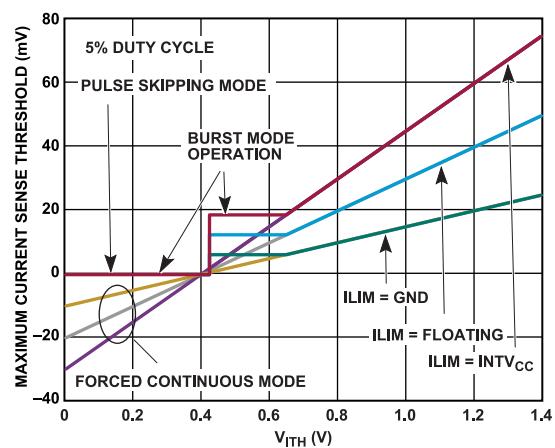
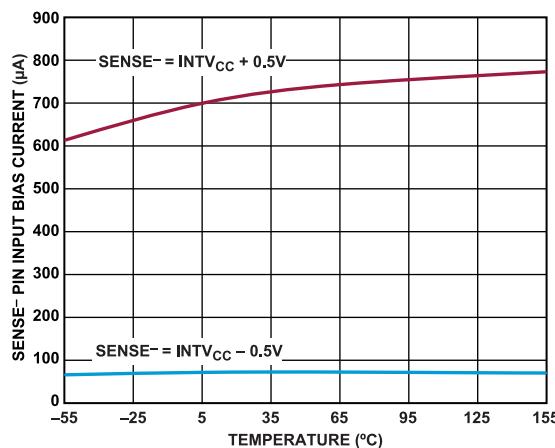
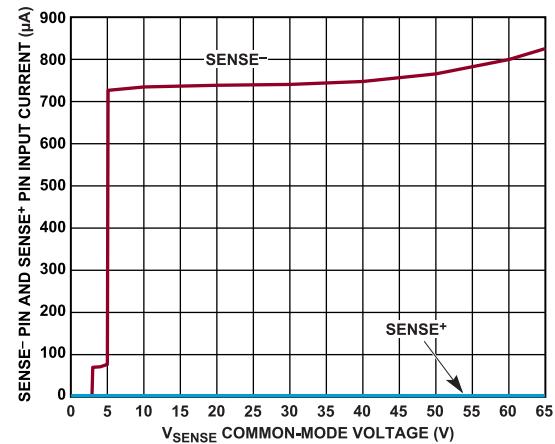
Figure 13. Maximum Current Sense Threshold vs. V_{ITH} 

Figure 14. SENSE- Pin Input Bias Current vs. Temperature

Figure 15. SENSE- Pin and SENSE+ Pin Input Current vs. V_{SENSE} Common-Mode Voltage

TYPICAL PERFORMANCE CHARACTERISTICS

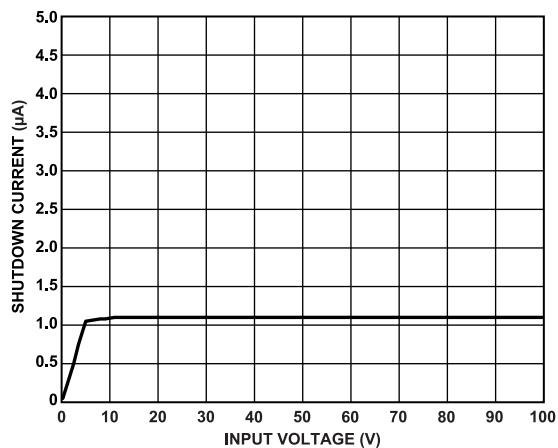


Figure 16. Shutdown Current vs. Input Voltage

016

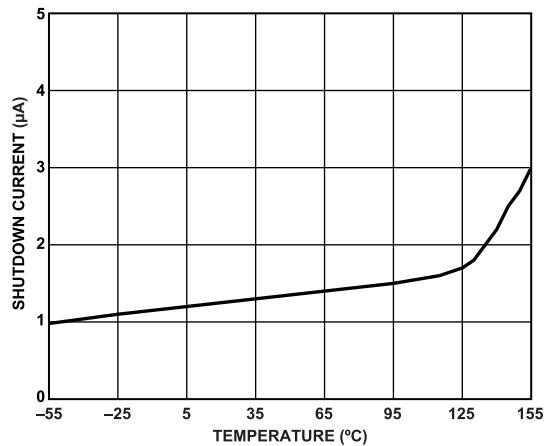


Figure 17. Shutdown Current vs. Temperature

017

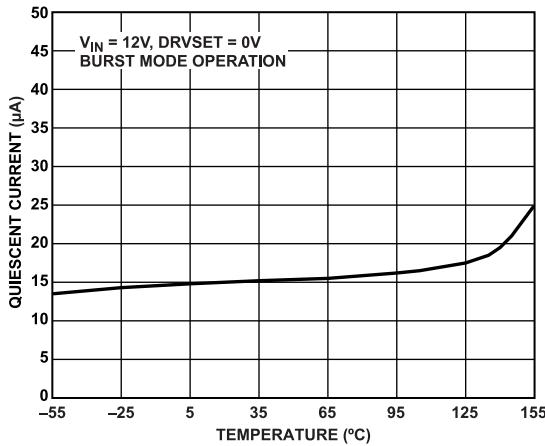


Figure 18. Quiescent Current vs. Temperature

018

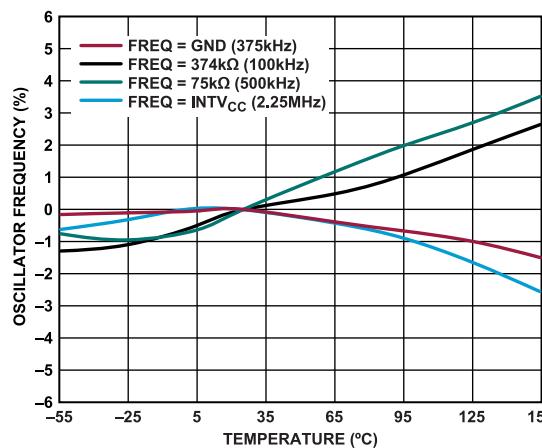


Figure 19. Oscillator Frequency vs. Temperature

019

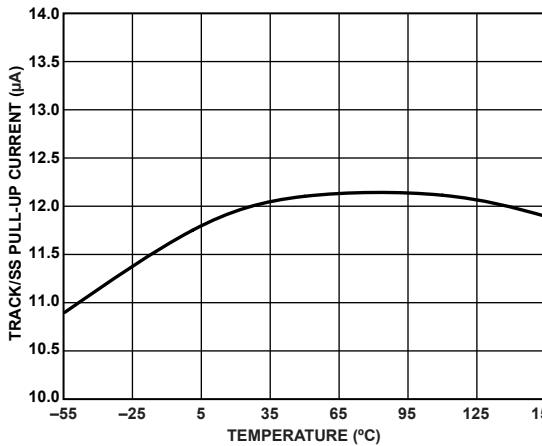


Figure 20. TRACK/SS Pull-Up Current vs. Temperature

020

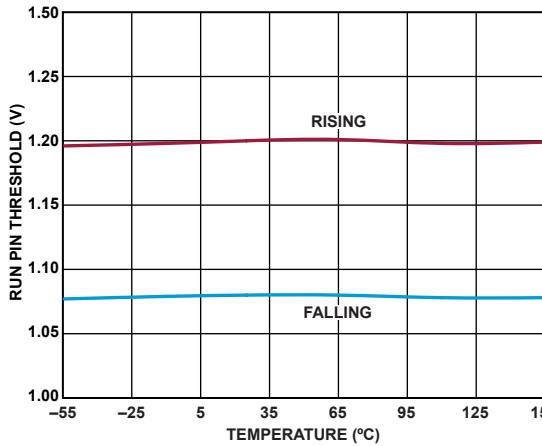
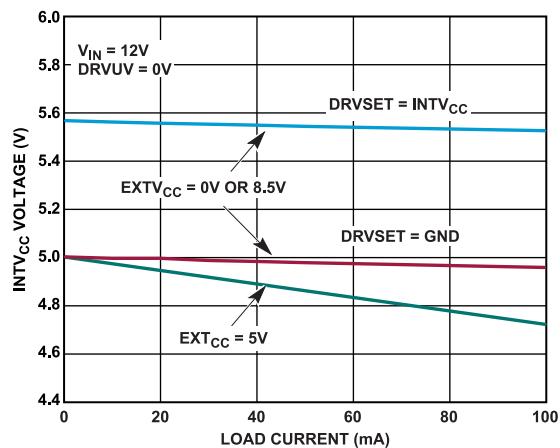


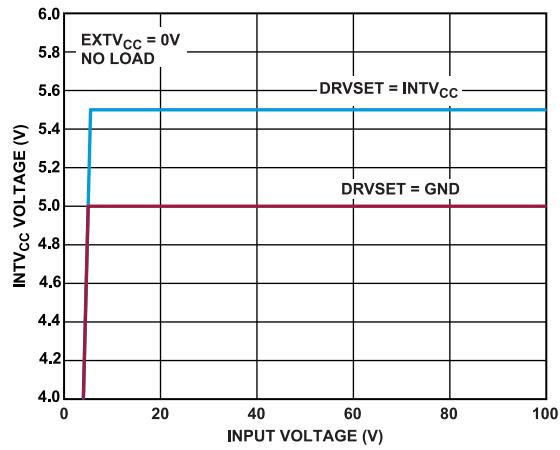
Figure 21. RUN Pin Threshold vs. Temperature

021

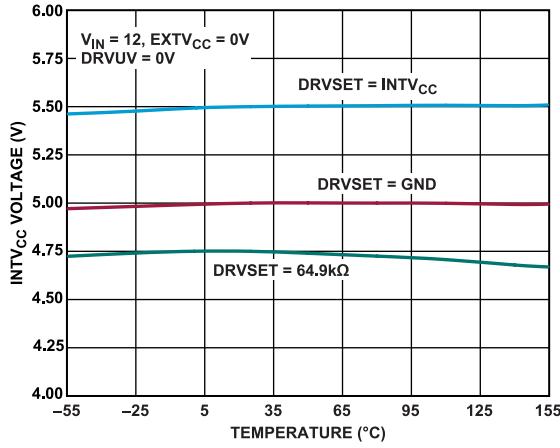
TYPICAL PERFORMANCE CHARACTERISTICS

Figure 22. INTV_{CC} Voltage vs. Load Current

022

Figure 23. INTV_{CC} Voltage vs. Input Voltage

023

Figure 24. INTV_{CC} Voltage vs. Temperature

024

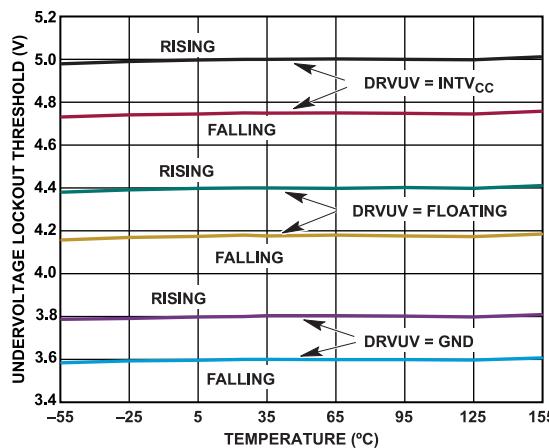
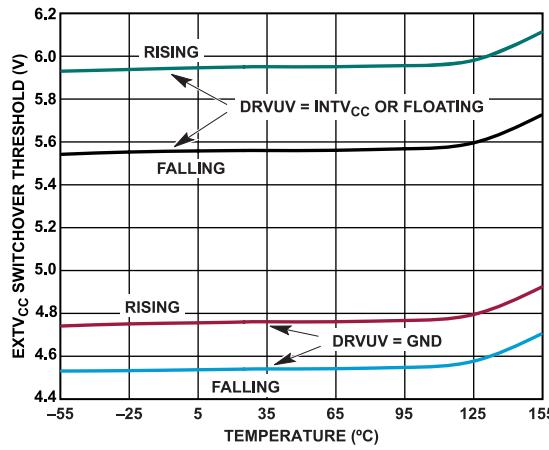


Figure 25. Undervoltage Lockout Threshold vs. Temperature

025

Figure 26. EXTV_{CC} Switchover Threshold vs. Temperature

026

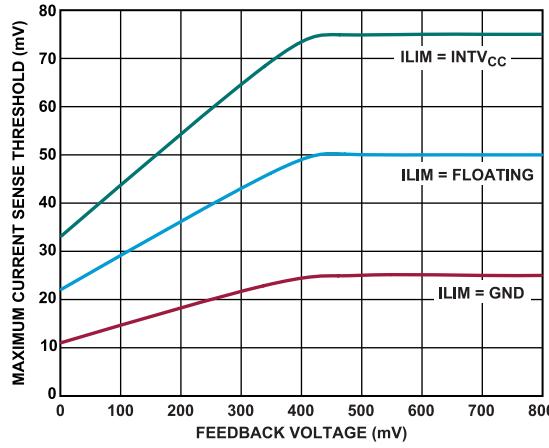


Figure 27. Maximum Current Sense Threshold vs. Feedback Voltage

027

TYPICAL PERFORMANCE CHARACTERISTICS

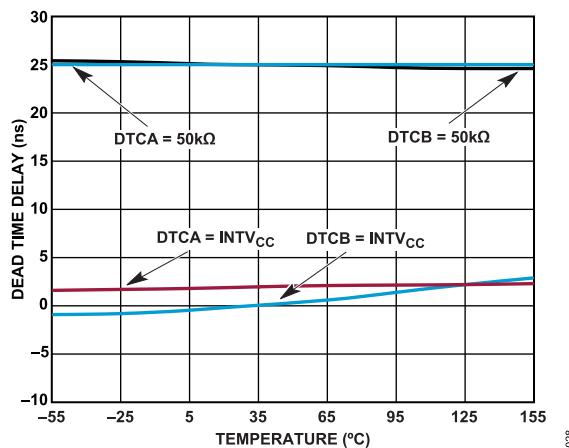


Figure 28. Dead Time Delay vs. Temperature

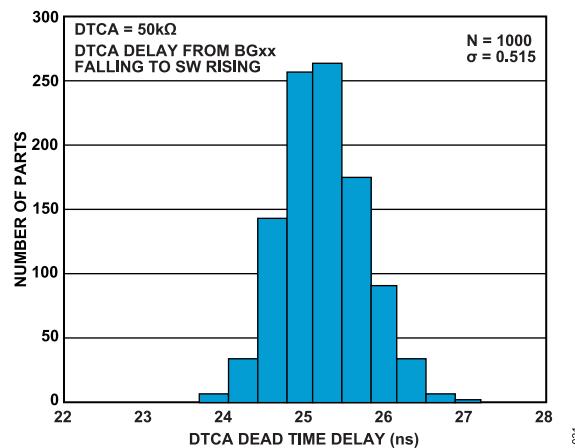


Figure 31. DTCA = 50 kΩ Dead Time Delay Histogram

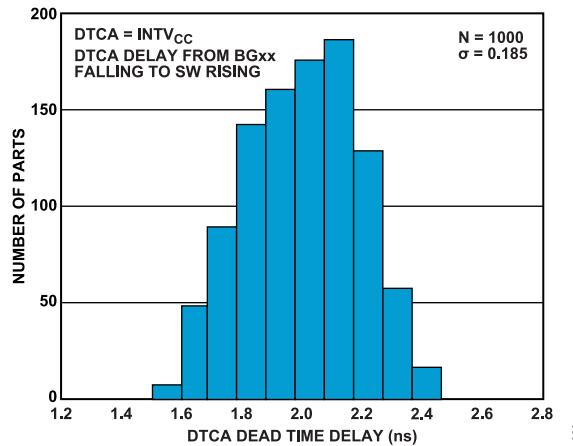
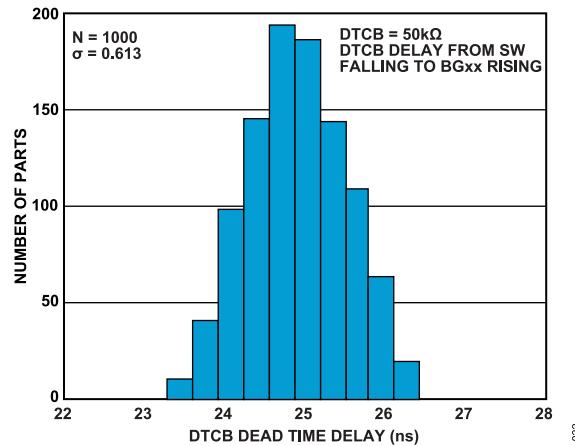
Figure 29. Smart Near Zero DTCA Dead Time Delay Histogram (δ Is the Standard Deviation of Dead Time Delay)

Figure 32. DTCB = 50 kΩ Dead Time Delay Histogram

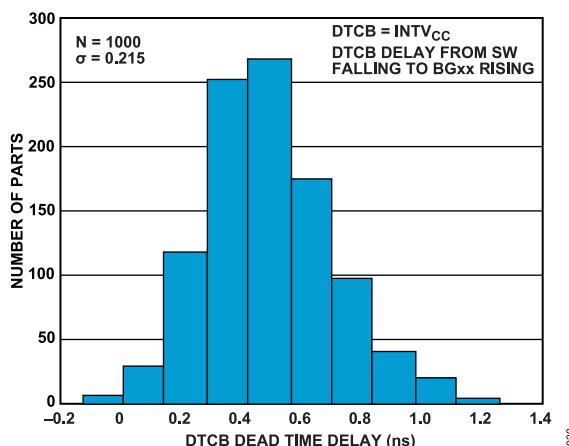


Figure 30. Smart Near Zero DTCB Dead Time Delay Histogram

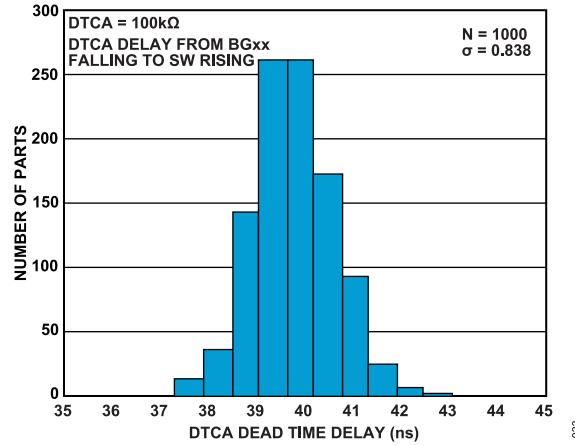


Figure 33. DTCA = 100 kΩ Dead Time Delay Histogram

TYPICAL PERFORMANCE CHARACTERISTICS

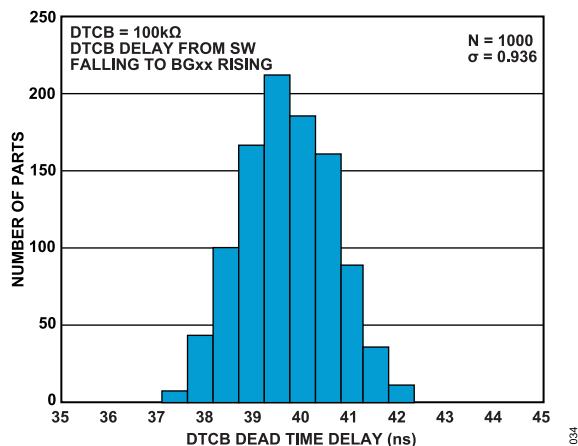


Figure 34. DTCB = 100 kΩ Dead Time Delay Histogram

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FUNCTIONAL DIAGRAM

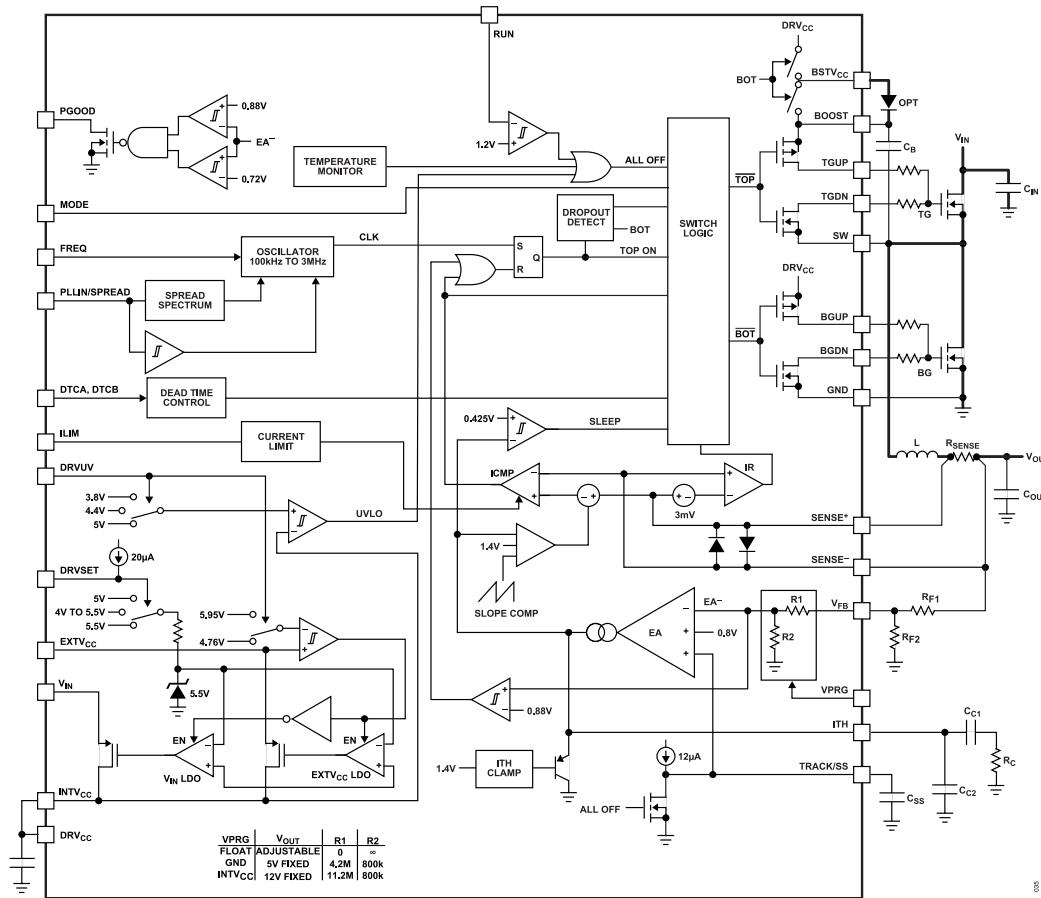


Figure 35. Functional Diagram

MAIN CONTROL LOOP

The LTC7891 is a synchronous controller using a constant frequency, peak current mode architecture. During normal operation, the external top FET turns on when the clock sets the set/reset (SR) latch, causing the inductor current to increase. The main switch turns off when the main current comparator, ICMP, resets the SR latch. After the top FET is turned off each cycle, the bottom FET turns on, which causes the inductor current to decrease until either the inductor current starts to reverse, as indicated by the current comparator (IR), or the beginning of the next clock cycle.

The peak inductor current at which ICMP trips and resets the latch is controlled by the voltage on the ITH pin, which is the output of the error amplifier (EA). The error amplifier compares the output voltage feedback signal at the V_{FB} pin (which is generated with an external resistor divider connected across the output voltage, V_{OUT} , to GND) to the internal 0.8 V reference voltage. When the load current increases, it causes a slight decrease in V_{FB} relative to the reference, which causes the EA to increase the ITH voltage until the average inductor current matches the new load current.

POWER AND BIAS SUPPLIES (V_{IN} , $EXTV_{CC}$, DRV_{CC} , AND $INTV_{CC}$)

The $INTV_{CC}$ pin supplies power for the top and bottom FET drivers and most of the internal circuitry. The supply for the FET drivers is derived from the DRV_{CC} pin, which must be tied to the $INTV_{CC}$ pin to supply power to the gate drivers. LDO linear regulators are available from both the V_{IN} pin and $EXTV_{CC}$ pin to provide power to $INTV_{CC}$, which can be programmed from 4 V to 5.5 V through control of the $DRVSET$ pin. When the $EXTV_{CC}$ pin is tied to a voltage below its switchover voltage, the V_{IN} LDO regulator supplies power to $INTV_{CC}$. If $EXTV_{CC}$ is taken above its switchover voltage, the V_{IN} LDO regulator turns off and the $EXTV_{CC}$ LDO regulator turns on. When enabled, the $EXTV_{CC}$ LDO regulator supplies power to $INTV_{CC}$. Using the $EXTV_{CC}$ pin allows the $INTV_{CC}$ power to be derived from a high efficiency external source, such as the LTC7891 switching regulator output.

HIGH-SIDE BOOTSTRAP CAPACITOR

The top FET driver is biased from the floating bootstrap capacitor (C_B), which normally recharges through an internal switch between BOOST and DRV_{CC} whenever the bottom FET turns on. The inter-

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nal switch is high impedance whenever the bottom FET is off, which prevents the bootstrap capacitor from overcharging whenever SW rings below GND during the dead times.

If the input voltage decreases to a voltage close to its output, the loop may enter dropout and attempt to turn on the top FET continuously. The dropout detector detects this event and forces the top FET off and the bottom FET on for a short time every tenth cycle to allow C_B to recharge, resulting in a 99% duty cycle at 370 kHz operation and approximately 98% duty cycle at 2 MHz operation. If the bootstrap capacitor voltage falls below approximately 75% of the $INTV_{CC}$ voltage, the boost refresh pulses increase to every fourth cycle to deliver more charge to C_B , resulting in slightly lower duty cycles in dropout.

DEAD TIME CONTROL (DTCA AND DTCB PINS)

The LTC7891 dead time delays can be programmed from near zero to 60 ns by configuring the DTCA and DTCB pins. The DTCA pin programs the dead time associated with the bottom FET turning off and the top FET turning on. The DTCB pin programs the dead time associated with top FET turning off and the bottom FET turning on. In this section, TG represents the voltage sensed at the top FET gate and BG represents the voltage sensed at the bottom FET gate.

Tying the DTCA pin to GND programs adaptive dead time control, which means the driver logic waits for the bottom FET to turn off before turning on the top FET. Adaptive dead time control results in dead times of approximately 20 ns between BG falling to TG rising.

Tying the DTCB pin to GND programs adaptive dead time control, which means the driver logic waits for the top FET to turn off before turning on the bottom FET. Adaptive dead time control results in dead times of approximately 20 ns between TG falling to BG rising.

Tying the DTCA pin to $INTV_{CC}$ programs smart near zero dead time control, which reduces the delay between the rising edge of SW to the falling edge of BG to near zero. Placing a resistor between the DTCA pin and GND adds additional delay between SW rising and BG falling from 7 ns to 60 ns. See the [Dead Time Control \(DTCA and DTCB Pins\)](#) section on dead time control for more information.

Tying the DTCB pin to $INTV_{CC}$ programs smart near zero dead time control, which reduces the delay between the falling edge of SW to the rising edge of BG to near zero. Placing a resistor between the DTCB pin and GND adds additional delay between SW falling and BG rising from 7 ns to 60 ns. See the [Dead Time Control \(DTCA and DTCB Pins\)](#) section on dead time control for more information.

STARTUP AND SHUTDOWN (RUN AND TRACK/SS PINS)

The LTC7891 can be shut down using the RUN pin. Pulling the RUN pin below 1.08 V shuts down the main control loop. Pulling the RUN pin below 0.7 V disables the controller and most internal

circuits, including the $INTV_{CC}$ LDO regulators. In this shutdown state, the LTC7891 draws only 1 μ A of quiescent current.

The RUN pin needs to be externally pulled up or driven directly by logic. The RUN pin can tolerate up to 100 V (absolute maximum). Therefore, the pin can be tied to V_{IN} in always on applications where the controller is enabled continuously and never shut down. Additionally, a resistive divider from V_{IN} to the RUN pin can be used to set a precise input undervoltage lockout so that the power supply does not operate below a user adjustable level.

The startup of V_{OUT} is controlled by the voltage on the TRACK/SS pin. When the voltage on the TRACK/SS pin is less than the 0.8 V internal reference voltage, the LTC7891 regulates the V_{FB} voltage to the TRACK/SS pin voltage instead of the 0.8 V reference voltage. This method allows the TRACK/SS pin to be used as a soft start, which smoothly ramps the output voltage on startup, limiting the input supply inrush current. An external capacitor from the TRACK/SS pin to GND is charged by an internal 12 μ A pull-up current, creating a voltage ramp on the TRACK/SS pin. As the TRACK/SS voltage rises linearly from 0 V to 0.8 V (and beyond), V_{OUT} rises smoothly from zero to its final value.

Alternatively, the TRACK/SS pin can be used to make the startup of V_{OUT} track that of another supply. Typically, this requires connecting to the TRACK/SS pin through an external resistor divider from the other supply to GND (see the [RUN Pin and Undervoltage Lockout](#) section and [Soft Start and Tracking \(TRACK/SS Pin\)](#) section).

LIGHT LOAD OPERATION: BURST MODE OPERATION, PULSE SKIPPING MODE, OR FORCED CONTINUOUS MODE (MODE PIN)

The LTC7891 can be set to enter high efficiency Burst Mode operation, constant frequency pulse skipping mode, or forced continuous conduction mode at light load currents.

To select Burst Mode operation, tie the MODE pin to GND. To select forced continuous operation, tie the MODE pin to $INTV_{CC}$. To select pulse skipping mode, tie the MODE pin to a dc voltage greater than 1.2 V and less than $INTV_{CC}$ – 1.3 V. An internal 100 $k\Omega$ resistor to GND invokes Burst Mode operation when the MODE pin is floating, and pulse skipping mode when the MODE pin is tied to $INTV_{CC}$ through an external 100 $k\Omega$ resistor.

When the controller is enabled for Burst Mode operation, the minimum peak current in the inductor is set to approximately 25% of its maximum value, even though the voltage on the ITH pin may indicate a lower value. If the average inductor current is higher than the load current, the EA decreases the voltage on the ITH pin. When the ITH voltage drops below 0.425 V, the internal sleep signal goes high (enabling sleep mode) and both external FETs turn off. The ITH pin is then disconnected from the output of the EA and parked at 0.45 V.

In sleep mode, much of the internal circuitry turns off, reducing the quiescent current drawn by the LTC7891 to 15 μ A. When V_{OUT} is

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3.2 V or higher, the majority of this quiescent current is supplied by the SENSE⁻ pin, which further reduces the input referred quiescent current by the ratio of V_{IN}/V_{OUT} multiplied by the efficiency.

In sleep mode, the load current is supplied by the output capacitor. As the output voltage decreases, the output of the EA rises. When the output voltage drops enough, the ITH pin is reconnected to the output of the EA, the sleep signal goes low, and the controller resumes normal operation by turning on the top FET on the next cycle of the internal oscillator.

When the controller is enabled for Burst Mode operation, the inductor current is not allowed to reverse. The IR turns off the bottom FET just before the inductor current reaches zero, preventing it from reversing and going negative. Therefore, the controller operates in discontinuous operation.

In forced continuous operation, the inductor current is allowed to reverse at light loads or under large transient conditions. The peak inductor current is determined by the voltage on the ITH pin, just as in normal operation. In this mode, the efficiency at light loads is lower than in Burst Mode operation. However, continuous operation has the advantage of lower output voltage ripple and less interference to audio circuitry. In forced continuous mode, the output ripple is independent of the load current.

When the MODE pin is connected for pulse skipping mode, the LTC7891 operates in pulse-width modulation (PWM) pulse skipping mode at light loads. In this mode, constant frequency operation is maintained down to approximately 1% of the designed maximum output current. At light loads, ICMP can remain tripped for several cycles and force the top FET to stay off for the same number of cycles (that is, skipping pulses). The inductor current is not allowed to reverse (discontinuous operation). This mode, like forced continuous operation, exhibits low output ripple as well as low audio noise and reduced RF interference, as compared to Burst Mode operation. Pulse skipping mode provides higher low current efficiency than forced continuous mode, but not nearly as high as Burst Mode operation.

Unlike forced continuous mode and pulse skipping mode, Burst Mode operation cannot be synchronized to an external clock. Therefore, if Burst Mode operation is selected and the switching frequency is synchronized to an external clock applied to the PLLIN/SPREAD pin, the LTC7891 switches from Burst Mode operation to forced continuous mode.

FREQUENCY SELECTION, SPREAD SPECTRUM, AND PHASE-LOCKED LOOP (FREQ AND PLLIN/SPREAD PINS)

The free running switching frequency of the LTC7891 controller is selected using the FREQ pin. Tying FREQ to GND selects 370 kHz, whereas tying FREQ to INTV_{CC} selects 2.25 MHz. Placing a resistor between FREQ and GND allows the frequency to be programmed between 100 kHz and 3 MHz.

Switching regulators can be particularly troublesome for applications where electromagnetic interference (EMI) is a concern. To improve EMI, the LTC7891 can operate in spread spectrum mode, which is enabled by tying the PLLIN/SPREAD pin to INTV_{CC}. This feature varies the switching frequency within typical boundaries of the frequency set by the FREQ pin and +20%.

A phase-locked loop (PLL) is available on the LTC7891 to synchronize the internal oscillator to an external clock source connected to the PLLIN/SPREAD pin. The PLL of the LTC7891 aligns the turn-on of the external top FET to the rising edge of the synchronizing signal.

The PLL frequency is prebiased to the free running frequency set by the FREQ pin before the external clock is applied. If prebiased near the external clock frequency, the PLL only needs to make slight changes to synchronize the rising edge of the external clock to the rising edge of TGxx. For more rapid lock in to the external clock, use the FREQ pin to set the internal oscillator to approximately the frequency of the external clock. The PLL of the LTC7891 is guaranteed to lock to an external clock source whose frequency is between 100 kHz and 3 MHz.

The PLLIN/SPREAD pin is transistor-transistor logic (TTL)-compatible with thresholds of 1.6 V (rising) and 1.1 V (falling), and is guaranteed to operate with a clock signal swing of 0.5 V to 2.2 V.

OUTPUT OVERVOLTAGE PROTECTION

The LTC7891 has an overvoltage comparator that guards against transient overshoots as well as other more serious conditions that can cause output overvoltage. When the V_{FB} pin rises more than 10% above its regulation point of 0.8 V, the top FET turns off and the inductor current is not allowed to reverse.

FOLDBACK CURRENT

When the output voltage falls to less than 70% of its nominal level, foldback current limiting is activated, progressively lowering the peak current limit in proportion to the severity of the overcurrent or short-circuit condition. Foldback current limiting is disabled during the soft start interval (as long as the V_{FB} voltage is keeping up with the TRACK/SS voltage).

POWER GOOD

The LTC7891 has a PGOOD pin that is connected to an open-drain of an internal N-channel MOSFET. The MOSFET turns on and pulls the PGOOD pin low when the V_{FB} voltage is not within $\pm 10\%$ of the 0.8 V reference. The PGOOD pin is also pulled low when the RUN pin is low (shutdown). When the V_{FB} voltage is within the $\pm 10\%$ requirement, the MOSFET turns off and the pin is allowed to be pulled up by an external resistor to a source no greater than 6 V, such as INTV_{CC}.

APPLICATIONS INFORMATION

Figure 1 is a basic LTC7891 application circuit. External component selection is largely driven by the load requirement and begins with the selection of the inductor, current sense components, operating frequency, and light load operating mode. The remaining power stage components, consisting of the input and output capacitors and power FETs, can then be chosen. Next, feedback resistors are selected to set the desired output voltage. Then, the remaining external components are selected, such as for soft start, biasing, and loop compensation.

INDUCTOR VALUE CALCULATION

The operating frequency and inductor selection are interrelated in that higher operating frequencies allow the use of smaller inductor and capacitor values. A higher frequency generally results in lower efficiency because of FET switching and gate charge losses. In addition to this trade-off, the effect of the inductor value on the ripple current and low current operation must also be considered. The inductor value has a direct effect on the ripple current.

The maximum average inductor current ($I_{L(MAX)}$) is equal to the maximum output current. The peak current is equal to the average inductor current plus half of the inductor ripple current (ΔI_L), which decreases with higher inductance (L) or higher frequency (f) and increases with higher V_{IN} , as shown in [Equation 1](#):

$$\Delta I_L = \frac{1}{(f)(L)} V_{OUT} \left(1 - \frac{V_{OUT}}{V_{IN}} \right) \quad (1)$$

Accepting larger values of ΔI_L allows the use of low inductances, but results in higher output voltage ripple and greater core losses. A reasonable starting point for setting ripple current is $\Delta I_L = 0.3 \times I_{L(MAX)}$. The maximum ΔI_L occurs at the maximum input voltage.

The inductor value also has secondary effects. The transition to Burst Mode operation begins when the average inductor current required results in a peak current below 25% of the current limit determined by R_{SENSE} . Lower inductor values (higher ΔI_L) cause this transition to occur at lower load currents, which can cause a dip in efficiency in the upper range of low current operation. In Burst Mode operation, lower inductance values cause the burst frequency to decrease.

INDUCTOR CORE SELECTION

When the value for L is known, select the type of inductor. High efficiency regulators generally cannot afford the core loss found in low cost powdered iron cores, forcing the use of more expensive ferrite or molypermalloy cores. Actual core loss is independent of core size for a fixed inductor value, but it is dependent on the inductance value selected. As inductance increases, core losses decrease. However, because increased inductance requires more turns of wire, copper losses increase.

Ferrite designs have low core loss and are preferred for high switching frequencies. Therefore, design goals can concentrate on copper loss and preventing saturation. Ferrite core material saturates hard, which means that inductance collapses abruptly

when the peak design current is exceeded. This collapse results in an abrupt increase in inductor ripple current and consequent output voltage ripple. Do not allow the core to saturate.

CURRENT SENSE SELECTION

The LTC7891 can be configured to use either inductor dc resistance (DCR) sensing or low value resistor sensing. The choice between the two current sensing schemes is a design trade-off between cost, power consumption, and accuracy. DCR sensing is popular because it saves expensive current sensing resistors and is more power efficient, particularly in high current applications. However, current sensing resistors provide the most accurate current limits for the controller. The selection of other external components is driven by the load requirement and begins with the selection of R_{SENSE} (if R_{SENSE} is used) and the inductor value.

The SENSE⁺ and SENSE⁻ pins are the inputs to the current comparator. The common-mode voltage range on these pins is 0 V to 65 V (the absolute maximum), enabling the LTC7891 to regulate output voltages up to a maximum of 60 V. The SENSE⁺ pin is high impedance, drawing less than $\approx 1 \mu A$. This high impedance allows the current comparator to be used in inductor DCR sensing. The impedance of the SENSE⁻ pin changes depending on the common-mode voltage. When less than $INTV_{CC} - 0.5$ V, the SENSE⁻ pin is relatively high impedance, drawing $\approx 1 \mu A$. When the SENSE⁻ pin is above $INTV_{CC} + 0.5$ V, a higher current ($\approx 700 \mu A$) flows into the pin. Between $INTV_{CC} - 0.5$ V and $INTV_{CC} + 0.5$ V, the current transitions from the smaller current to the higher current. The SENSE⁻ pin has an additional $\approx 70 \mu A$ current when its voltage is above 3.2 V to bias internal circuitry from V_{OUT} instead of V_{IN} , which reduces the input referred supply current.

Filter components mutual to the sense lines must be placed close to the LTC7891, and the sense lines must run close together to a Kelvin connection underneath the current sense element (shown in [Figure 36](#)). Sensing current elsewhere can effectively add parasitic inductance and capacitance to the current sense element, degrading the information at the sense terminals and making the programmed current limit unpredictable. If DCR sensing is used ([Figure 38](#)), the R1 resistor must be placed close to the switching node to prevent noise from coupling into sensitive small signal nodes.

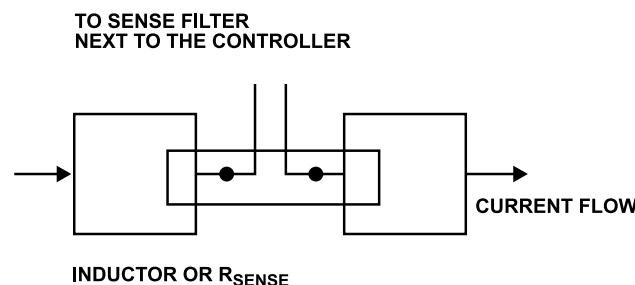


Figure 36. Sense Lines Placement with Inductor or Sense Resistor

APPLICATIONS INFORMATION

LOW VALUE RESISTOR CURRENT SENSING

Figure 37 shows a typical sensing circuit using a discrete resistor. R_{SENSE} is chosen based on the required output current. The current comparator of the controller has a $V_{SENSE(MAX)}$ of 50 mV, 25 mV, or 75 mV, as determined by the state of the ILIM pin. The current comparator threshold voltage sets the peak inductor current.

Using the maximum inductor current ($I_{L(MAX)}$) and ripple current (ΔI_L) (as described in the [Inductor Value Calculation](#) section), the target sense resistor value is given by [Equation 2](#), as follows:

$$R_{SENSE} = \frac{V_{SENSE(MAX)}}{I_{L(MAX)} + \frac{\Delta I_L}{2}} \quad (2)$$

To ensure that the application delivers the full load current over the full operating temperature range, choose the minimum value for $V_{SENSE(MAX)}$ in [Table 1](#).

The parasitic inductance (ESL) of the sense resistor introduces significant error in the current sense signal for lower inductor value (<3 μ H) or higher current (>5 A) applications. This error is proportional to the input voltage and can degrade line regulation or cause loop instability. Placing an RC filter (R_F) into the sense pins, as shown in [Figure 37](#), can be used to compensate for this error. For optimal cancellation of the ESL, set the RC filter time constant to $R_F \times C_F = ESL/R_{SENSE}$ (C_F is the filter capacitor). In general, select C_F to be in the range of 1 nF to 10 nF and calculate the corresponding R_F . Surface-mount sense resistors in low ESL, wide footprint geometries are recommended to minimize this error. If not specified in the data sheet of the manufacturer, the ESL can be approximated as 0.4 nH for a resistor with a 1206 footprint, and 0.2 nH for a resistor with a 1225 footprint.

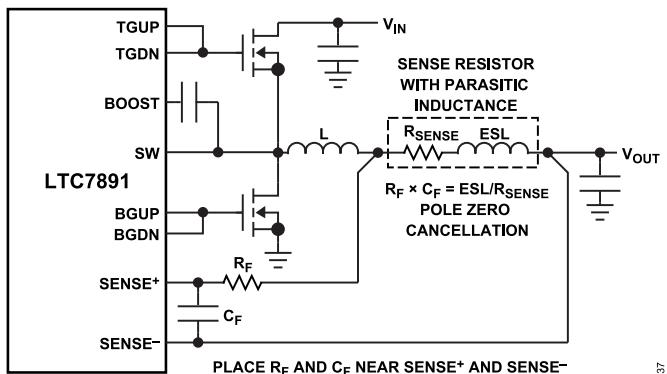


Figure 37. Using a Resistor to Sense Current

INDUCTOR DCR CURRENT SENSING

For applications requiring the highest possible efficiency at high load currents, the LTC7891 is capable of sensing the voltage drop across the inductor DCR, as shown in [Figure 38](#). The DCR of the inductor represents the small amount of dc winding resistance of the copper, which can be less than 1 m Ω for low value, high current inductors. In a high current application requiring such an

inductor, power loss through a sense resistor costs several points of efficiency compared to inductor DCR sensing.

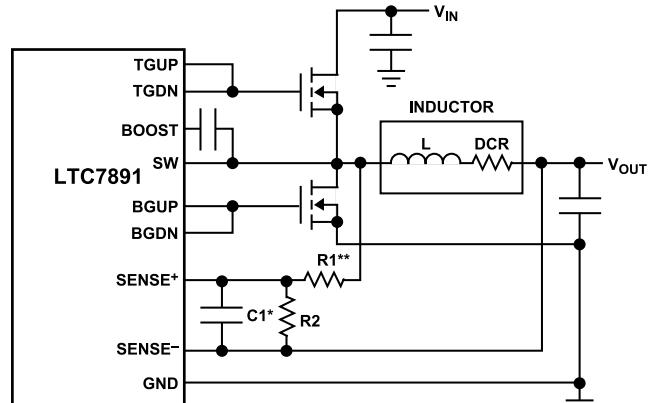


Figure 38. Using the Inductor DCR to Sense Current ($R_{SENSE(EQUIV)}$ Is Equivalent Sensed Resistance)

If the external $(R1||R2) \times C1$ time constant is chosen to be equal to the L/DCR time constant, the voltage drop across the external capacitor is equal to the drop across the inductor DCR multiplied by $R2/(R1+R2)$. $R2$ scales the voltage across the sense terminals for applications where the DCR is greater than the target sense resistor value. To properly dimension the external filter components, the DCR of the inductor must be known. The DCR can be measured using an inductance, capacitance, and resistance (LCR) meter. However, the DCR tolerance is not always the same and varies with temperature. Consult the data sheet of the manufacturer for detailed information.

Using $I_{L(MAX)}$ and ΔI_L (as described in the [Inductor Value Calculation](#) section), the target sense resistor value is given by [Equation 3](#), as follows:

$$R_{SENSE(EQUIV)} = \frac{V_{SENSE(MAX)}}{I_{L(MAX)} + \frac{\Delta I_L}{2}} \quad (3)$$

To ensure that the application delivers the full load current over the full operating temperature range, choose the minimum value for $V_{SENSE(MAX)}$ in [Table 1](#).

Next, determine the DCR of the inductor. When provided, use the maximum value noted by the manufacturer, typically given at 20°C. Increase this value to account for the temperature coefficient of copper resistance, which is approximately 0.4%/°C. A conservative value for the maximum inductor temperature ($T_{L(MAX)}$) is 100°C. To scale the maximum inductor DCR (DCR_{MAX}) to the desired sense resistor (R_D) value, use the divider ratio given by [Equation 4](#), as follows:

$$R_D = \frac{R_{SENSE(EQUIV)}}{DCR_{MAX} \text{ at } T_{L(MAX)}} \quad (4)$$

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C1 is typically selected to be in the range of 0.1 μ F to 0.47 μ F. This range forces the equivalent resistance ($R1||R2$) to around 2 k Ω , reducing the error that can result from the ≈ 1 μ A current of the SENSE⁺ pin.

$R1||R2$ is scaled to the room temperature inductance and the maximum DCR given by [Equation 5](#), as follows:

$$R1 \parallel R2 = \frac{L}{(DCR \text{ at } 20^\circ C) \times C1} \quad (5)$$

The sense resistor values are given by [Equation 6](#) and [Equation 7](#), as follows:

$$R1 = \frac{R1 \parallel R2}{R_D} \quad (6)$$

$$R2 = \frac{R1 \times R_D}{1 - R_D} \quad (7)$$

The maximum power loss (P_{LOSS}) in R1 is related to duty cycle and occurs in continuous mode at the maximum input voltage ($V_{IN(MAX)}$) given by [Equation 8](#), as follows:

$$P_{LOSS} \text{ in } R1 = \frac{(V_{IN(MAX)} - V_{OUT}) \times V_{OUT}}{R1} \quad (8)$$

Ensure that R1 has a power rating higher than P_{LOSS} in R1. If high efficiency is necessary at light loads, consider this power loss when deciding whether to use DCR sensing or sense resistors. Light load power loss can be modestly higher with a DCR network than with a sense resistor, due to the extra switching losses incurred through R1. However, DCR sensing eliminates a sense resistor, reduces conduction losses, and provides higher efficiency at heavy loads. Peak efficiency is about the same with either method.

SETTING THE OPERATING FREQUENCY

Selecting the operating frequency is a trade-off between efficiency and component size. High frequency operation allows the use of smaller inductor and capacitor values. Operation at lower frequencies improves efficiency by reducing gate charge and transition losses, but requires larger inductance values and/or more output capacitance to maintain low output ripple voltage.

In higher voltage applications, transition losses contribute more significantly to power loss, and a proper balance between size and efficiency is achieved with a switching frequency between 300 kHz and 900 kHz. Lower voltage applications benefit from lower switching losses, and can operate at switching frequencies up to 3 MHz, if desired. The switching frequency is set using the FREQ and PLLIN/SPREAD pins, as shown in [Table 4](#).

Table 4. Setting the Switching Frequency Using FREQ and PLLIN/SPREAD

FREQ Pin	PLLIN/SPREAD Pin	Frequency
0 V	0 V	370 kHz
INTV _{CC}	0 V	2.25 MHz
Resistor to GND	0 V	100 kHz to 3 MHz
0 V, INTV _{CC} , or Resistor to GND	External clock, 100 kHz to 3 MHz	Phase-locked to external clock
0 V, INTV _{CC} , or Resistor to GND	INTV _{CC}	Spread spectrum, f _{osc} modulated 0% to +20%

Tying the FREQ pin to GND selects 370 kHz, whereas tying FREQ to INTV_{CC} selects 2.25 MHz. Placing a resistor between FREQ and GND allows the frequency to be programmed anywhere between 100 kHz and 3 MHz. Choose a FREQ pin resistor (R_{FREQ}) from [Figure 39](#) or [Equation 9](#), as follows:

$$R_{FREQ} \text{ (in } k\Omega) = \frac{37 \text{ MHz}}{f_{OSC}} \quad (9)$$

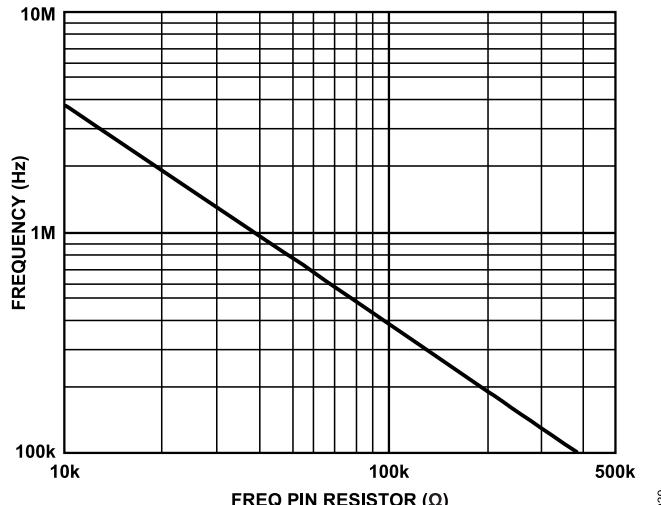


Figure 39. Relationship Between Oscillator Frequency and Resistor Value at the FREQ Pin

To improve EMI performance, spread spectrum mode can be selected by tying the PLLIN/SPREAD pin to INTV_{CC}. When spread spectrum mode is enabled, the switching frequency modulates within the frequency selected by the FREQ pin and +20%. Spread spectrum mode can be used in any operating mode selected by the MODE pin (Burst Mode, pulse skipping, or forced continuous mode).

A PLL is also available on the LTC7891 to synchronize the internal oscillator to an external clock source connected to the PLLIN/SPREAD pin. After the PLL locks, TGxx is synchronized to the rising edge of the external clock signal. See the [Phase-Locked Loop and Frequency Synchronization](#) section for details.

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SELECTING THE LIGHT LOAD OPERATING MODE

The LTC7891 can be set to enter high efficiency Burst Mode operation, constant frequency pulse skipping mode, or forced continuous conduction mode at light load currents. To select Burst Mode operation, tie the MODE pin to GND. To select forced continuous operation, tie the MODE pin to INTV_{CC}. To select pulse skipping mode, tie the MODE pin to INTV_{CC} through a 100 kΩ resistor. An internal 100 kΩ resistor from the MODE pin to GND selects Burst Mode if the pin is floating. When synchronized to an external clock through the PLLIN/SPREAD pin, the LTC7891 operates in pulse skipping mode if it is selected. Otherwise, the LTC7891 operates in forced continuous mode. Table 5 summarizes the use of the MODE pin to select the light load operating mode.

Table 5. Using the MODE Pin to Select Light Load Operating Mode

MODE Pin	Light Load Operating Mode	Mode When Synchronized
0 V or Floating	Burst Mode	Forced continuous
100 kΩ to INTV _{CC}	Pulse skipping	Pulse skipping
INTV _{CC}	Forced continuous	Forced continuous

The requirements of each application dictate the appropriate choice for light load operating mode. In Burst Mode operation, the inductor current is not allowed to reverse. The reverse current comparator turns off the bottom FET before the inductor current reaches zero, preventing it from reversing and going negative. Therefore, the regulator operates in discontinuous operation. In addition, when the load current is light, the inductor current begins bursting at frequencies lower than the switching frequency and enters a low current sleep mode when not switching. As a result, Burst Mode operation has the highest possible efficiency at light loads.

In forced continuous mode, the inductor current is allowed to reverse at light loads and switches at the same frequency regardless of the load. In this mode, the efficiency at light loads is considerably lower than in Burst Mode operation. However, continuous operation has the advantage of lower output voltage ripple and less interference to audio circuitry. In forced continuous mode, the output ripple is independent of the load current.

In pulse skipping mode, constant frequency operation is maintained down to approximately 1% of the designed maximum output current. At very light loads, the PWM comparator can remain tripped for several cycles and force the top FET to remain off for the same number of cycles (that is, skipping pulses). The inductor current is not allowed to reverse (discontinuous operation). This mode, like forced continuous operation, exhibits low output ripple as well as low audio noise and reduced RF interference compared to Burst Mode operation. Pulse skipping mode provides higher light load efficiency than forced continuous mode, but not nearly as high as Burst Mode operation. Consequently, pulse skipping mode represents a compromise between light load efficiency, output ripple, and EMI.

In some applications, it may be desirable to change the light load operating mode based on the conditions present in the system. For example, if a system is inactive, the user can select high efficiency Burst Mode operation by keeping the MODE pin set to 0 V. When the system wakes, the user can send an external clock to PLLIN/SPREAD, or tie MODE to INTV_{CC} to switch to low noise forced continuous mode. These on-the-fly mode changes can allow an individual application to benefit from the advantages of each light load operating mode.

DEAD TIME CONTROL (DTCA AND DTCB PINS)

The dead time delays of the LTC7891 can be adjusted from near zero to 60 ns by configuring the DTCA pin and DTCB pin. Refer to Figure 40, Figure 41, and Figure 42, which show the TG minus SW, BG, and SW waveforms for each DTCx pin setting. In the DTCx Pins Tied to GND (Adaptive Dead Time Control), DTCx Pins Tied to INTV_{CC} (Smart Near Zero Dead Time Control), and DTCx Pins Connected with a Resistor to GND sections, TG represents the voltage sensed at the top FET gate (the threshold for TG falling is sensed at the TGUP pin), and BG represents the voltage sensed at the bottom FET gate (the thresholds for BG rising and falling are sensed at the BGDN and BGUP pins, respectively). The SW waveforms represent operation in continuous conduction mode with positive inductor current. The DTCA pin programs the dead time associated with the bottom FET turning off and the top FET turning on (SW transitioning from low to high). The DTCB pin programs the dead time associated with top FET turning off and the bottom FET turning on (SW transitioning from high to low).

DTCx Pins Tied to GND (Adaptive Dead Time Control)

Tying the DTCA pin and DTCB pin to GND programs adaptive dead time control. In adaptive control (see Figure 40), the dead time is measured between one FET turning off and the other FET turning on. Tying the DTCA pin to GND fixes the delay between BG going low and TG minus SW going high to approximately 20 ns. Tying the DTCB pin to GND fixes the delay between TG minus SW falling and BG rising to approximately 20 ns.

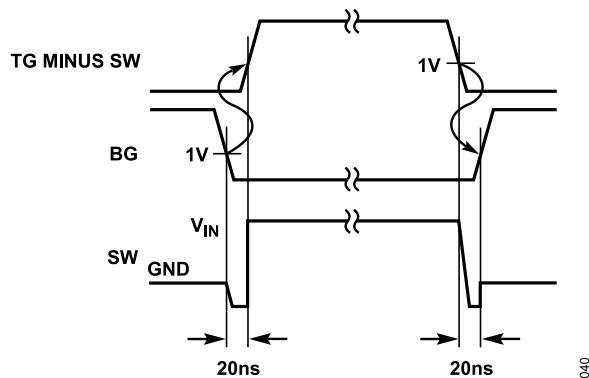


Figure 40. DTCx Pins Tied to GND—Adaptive Dead Time Control

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DTCx Pins Tied to INTV_{CC} (Smart Near Zero Dead Time Control)

Figure 41 shows the timing waveforms when the DTCx pins are tied to INTV_{CC}. Tying the DTCA pin to INTV_{CC} reduces the delay between BG falling and SW rising to near zero. Tying the DTCB pin to INTV_{CC} reduces the delay between SW falling and BG rising to near zero (with positive inductor current when the top FET turns off). Note the rising edge of BG (sensed at the BGDN pin) and SW is defined as the moment its voltage rises to ~1 V (with respect to GND). Likewise, the falling edge of BG (sensed at the BGUP pin) and SW is the moment its voltage falls to ~1 V.

For the DTCB transition, if the SW node does not fall to 1 V approximately 20 ns after the top FET turns off (inductor current is small or negative), the bottom FET turns on automatically. This 20 ns timeout sets the maximum delay between TG minus SW falling and BG rising.

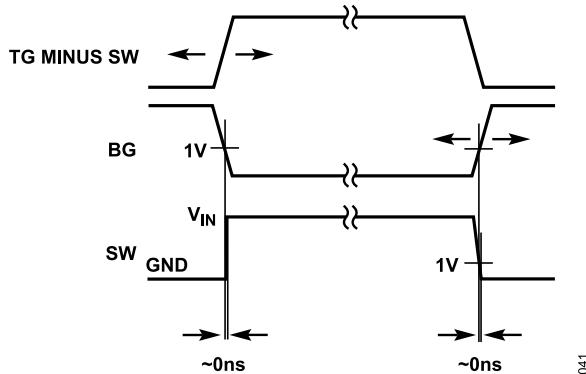


Figure 41. DTCx Pins Tied to INTV_{CC}—Smart Near Zero Dead Time Control

DTCx Pins Connected with a Resistor to GND

Connecting a resistor between the DTCx pins and GND programs an additional delay from 7 ns to 60 ns between the SW and BG edges (see Figure 42). A resistor tied to the DTCA pin inserts additional delay between BG falling and SW rising.

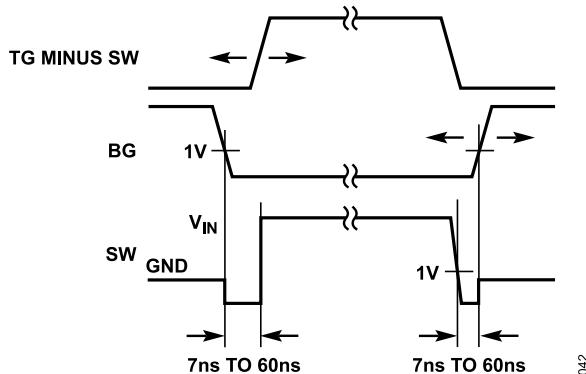


Figure 42. DTCx Pins with Resistor to GND—Adjustable Dead Time Control

A resistor tied to the DTCB pin to GND inserts an additional delay between SW falling and BG rising. Figure 43 shows the relationship

between the DTCx pin resistor value and the programmed delay between the BG and SW edges. This resistor must not be less than 10 kΩ.

With a resistor on the DTCx pins, the maximum delay between one FET turning off and the other FET turning on is set to approximately 30 ns beyond the programmed delay time. For the DTCA transition (SW from low to high), this timeout can be reached if the bottom FET turns off with negative inductor current (for example, light load currents in forced continuous mode), such that SW slews high immediately after the bottom FET turns off.

If one of the DTCx pins is programmed with a resistor, the other DTCx pin must be programmed with a resistor or tied to INTV_{CC} for proper dead time control operation. Unexpected dead time delays can result if one DTCx pin is programmed with a resistor or tied to INTV_{CC}, while the other DTCx pin is tied to GND.

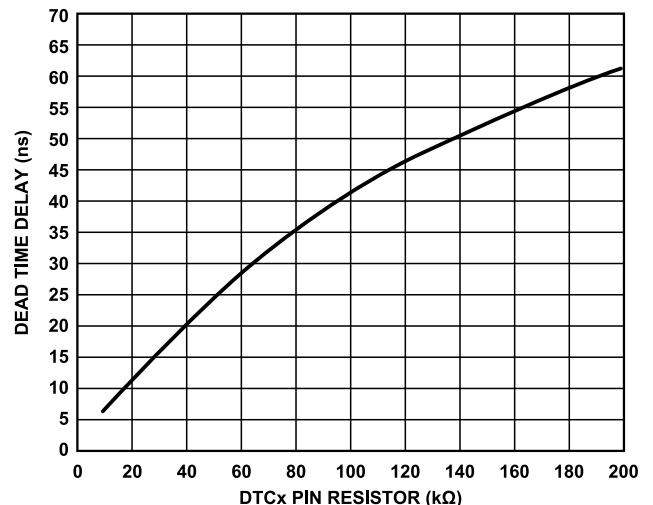


Figure 43. Relationship Between Dead Time Delay and Resistor Value at DTCx Pins

Power FET Selection

Two external power FETs must be selected for the LTC7891: one N-channel FET for the top (main) switch and one N-channel FET for the bottom (synchronous) switch. The peak-to-peak gate drive levels are set by the INTV_{CC} regulation point (4 V to 5.5 V). Most GaN FETs can be driven comfortably within this INTV_{CC} regulation window. If using silicon MOSFETs, logic level threshold MOSFETs must be used in most applications. Pay close attention to the breakdown voltage (BVD_{SS}) specification for the FETs as well.

Selection criteria for the power FETs include the on resistance ($R_{DS(ON)}$), Miller capacitance (C_{MILLER}), input voltage, and maximum output current. C_{MILLER} can be approximated from the gate charge curve typically provided in the data sheet of the FET manufacturer. C_{MILLER} is equal to the increase in gate charge along the horizontal axis while the curve is approximately flat, divided by the specified change in the voltage difference between the drain and source terminals of the MOSFET (V_{DS}). This result is then multiplied by

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the ratio of the application applied V_{DS} to the gate charge curve specified V_{DS} . When the IC is operating in continuous mode, the duty cycles for the top and bottom FETs are given by [Equation 10](#) and [Equation 11](#), as follows:

$$\text{Main Switch Duty Cycle} = \frac{V_{OUT}}{V_{IN}} \quad (10)$$

$$\text{Synchronous Switch Duty Cycle} = \frac{V_{IN} - V_{OUT}}{V_{IN}} \quad (11)$$

The FET power dissipations at the maximum output current are given by [Equation 12](#) and [Equation 13](#), as follows:

$$\begin{aligned} P_{MAIN} &= \frac{V_{OUT}}{V_{IN}} (I_{MAX})^2 (1 + \delta) R_{DS(ON)} + (V_{IN})^2 \\ &\quad \left(\frac{I_{MAX}}{2} \right) (R_{DR}) (C_{MILLER}) \times \\ &\quad \left(\frac{1}{V_{INTCC} - V_{THMIN}} + \frac{1}{V_{THMIN}} \right) (f) \end{aligned} \quad (12)$$

$$P_{SYNC} = \frac{V_{IN} - V_{OUT}}{V_{IN}} (I_{MAX})^2 (1 + \delta) R_{DS(ON)} \quad (13)$$

where:

P_{MAIN} is the power dissipation from the main switch.

V_{INTCC} is the $INTV_{CC}$ voltage.

P_{SYNC} is the power dissipation from the synchronous switch.

δ is the temperature dependency of $R_{DS(ON)}$ ($\delta \approx 0.005/^\circ\text{C}$).

R_{DR} is the effective driver resistance at the Miller threshold voltage of the FET ($R_{DR} \approx 2 \Omega$).

V_{THMIN} is the typical FET minimum threshold voltage.

Both FETs have I^2R losses (I^2R is the power loss equation of the FETs), whereas the main N-channel equations include an additional term for transition losses, which are highest at high input voltages. For $V_{IN} < 20$ V, the high current efficiency generally improves with larger FETs. However, for $V_{IN} > 20$ V, the transition losses rapidly increase to the point that the use of a higher $R_{DS(ON)}$ device with lower C_{MILLER} provides higher efficiency. The synchronous FET losses are greatest at high input voltage when the top switch duty factor is low or during a short-circuit when the synchronous switch is on close to 100% of the period.

 C_{IN} AND C_{OUT} SELECTION

The selection of the input capacitance (C_{IN}) is usually based on the worst case rms current drawn through the input network (battery, fuse, or capacitor). The highest $V_{OUT} \times I_{OUT}$ product needs to be used in [Equation 14](#) to determine the maximum rms capacitor current requirement.

In continuous mode, the source current of the top FET is a square wave of duty cycle V_{OUT}/V_{IN} . To prevent large voltage transients, use a low effective series resistance (ESR) capacitor sized for the maximum rms current (I_{RMS}). At I_{MAX} , the maximum rms capacitor current is given by [Equation 14](#), as follows:

$$\begin{aligned} &C_{IN} \text{ Required } I_{RMS} \\ &\approx \frac{I_{MAX}}{V_{IN}} ((V_{OUT})(V_{IN} - V_{OUT}))^{1/2} \end{aligned} \quad (14)$$

[Equation 14](#) has a maximum at $V_{IN} = 2 V_{OUT}$, where $I_{RMS} = I_{OUT}/2$ (I_{OUT} is the output current). This simple worst case condition is commonly used for design because even significant deviations do not offer much relief. Note that the ripple current ratings of capacitor manufacturers are often based on only 2000 hours of life. This basis makes it advisable to further derate the capacitor, or to choose a capacitor rated at a higher temperature than required. Several capacitors can be paralleled to meet size or height requirements in the design. Due to the high operating frequency of the LTC7891, ceramic capacitors can also be used for C_{IN} . Consult the manufacturer if there is any question.

Placing a small (0.1 μF to 1 μF) bypass capacitor between the chip V_{IN} pin and GND close to the LTC7891 is also suggested. An optional 1 Ω to 10 Ω resistor placed between C_{IN} and the V_{IN} pin provides further isolation from a noisy input supply.

The selection of the output capacitance (C_{OUT}) is driven by the ESR. Typically, once the ESR requirement is satisfied, the capacitance is adequate for filtering. The output ripple (ΔV_{OUT}) is approximated to [Equation 15](#), as follows:

$$\Delta V_{OUT} \approx \Delta I_L (ESR + \frac{1}{8fC_{OUT}}) \quad (15)$$

where:

f is the operating frequency.

ΔI_L is the ripple current in the inductor.

The output ripple is highest at the maximum input voltage because ΔI_L increases with the input voltage.

SETTING THE OUTPUT VOLTAGE

The LTC7891 output voltages are set by an external feedback resistor divider carefully placed across the output, as shown in [Figure 44](#) and [Figure 45](#). The regulated output voltage is determined by [Equation 16](#), as follows:

$$V_{OUT} = 0.8V \left(1 + \frac{R_B}{R_A} \right) \quad (16)$$

Place the R_A and R_B resistors close to the V_{FB} pin to minimize PCB trace length and noise on the sensitive V_{FB} node. Take care to route the V_{FB} trace away from noise sources, such as the inductor or the SW trace. To improve frequency response, a feedforward capacitor (C_{FF}) can be used.

The LTC7891 can be programmed to a fixed 12 V or 5 V output through control of the VPRG pin. [Figure 45](#) shows how the V_{FB} pin is issued to sense the output voltage in fixed output mode. Tying VPRG to $INTV_{CC}$ or GND programs V_{OUT} to 12 V or 5 V, respectively. Floating VPRG sets V_{OUT} to adjustable output mode using external resistors.

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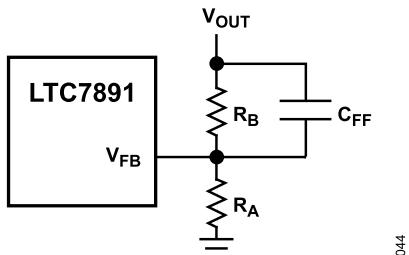


Figure 44. Setting Adjustable Output Voltage

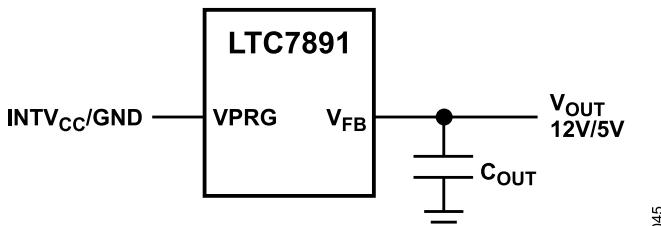


Figure 45. Setting Fixed 12 V or 5 V Voltage

RUN PIN AND UNDERVOLTAGE LOCKOUT

The LTC7891 is enabled using the RUN pin. The RUN pin has a rising threshold of 1.2 V with 100 mV of hysteresis. Pulling the RUN pin below 1.08 V shuts down the main control loop and resets the soft start. Pulling the RUN pin below 0.7 V disables the controller and most internal circuits, including the INTV_{CC} LDO regulators. In this state, the LTC7891 draws only $\approx 1 \mu\text{A}$ of quiescent current.

The RUN pin is high impedance, must be externally pulled up or pulled down, and is driven directly by logic. The RUN pin can tolerate up to 100 V (the absolute maximum). Therefore, the pin can be conveniently tied to V_{IN} in always on applications where the controller is enabled continuously and never shut down. Do not float the RUN pin.

The RUN pin can also be configured as a precise UVLO on the input supply with a resistor divider from V_{IN} to GND, as shown in Figure 46.

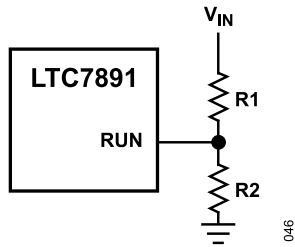


Figure 46. Using the RUN Pin as a UVLO

The V_{IN} UVLO thresholds can be computed by Equation 17 and Equation 18, as follows:

$$\text{UVLO Rising} = 1.2V \left(1 + \frac{R1}{R2}\right) \quad (17)$$

$$\text{UVLO Falling} = 1.08V \left(1 + \frac{R1}{R2}\right) \quad (18)$$

The current that flows through the R1 and R2 divider adds to the shutdown, sleep, and active current of the LTC7891. Take care to minimize the impact of this current on the overall efficiency of the application circuit. Resistor values in the MΩ range can be required to keep the impact on quiescent shutdown and sleep currents low.

SOFT START AND TRACKING (TRACK/SS PIN)

The startup of V_{OUT} is controlled by the voltage on the TRACK/SS pin. When the voltage on the TRACK/SS pin is less than the internal 0.8 V reference, the LTC7891 regulates the V_{FB} pin voltage to the voltage on the TRACK/SS pin instead of the internal reference. The TRACK/SS pin can be used to program an external soft start function, or to allow V_{OUT} to track another supply during startup.

Soft start is enabled by connecting a capacitor from the TRACK/SS pin to GND. An internal 12 μA current source charges the capacitor, providing a linear ramping voltage at the TRACK/SS pin. The LTC7891 regulates its feedback voltage (and hence V_{OUT}) according to the voltage on the TRACK/SS pin, allowing V_{OUT} to rise smoothly from 0 V to its final regulated value. For a desired soft start time (t_{SS}), select a soft start capacitor (C_{SS}) = t_{SS} × 15 nF/ms.

Alternatively, the TRACK/SS pin can be used to track another supply during startup, as shown qualitatively in Figure 47 and Figure 48. To track another supply, connect a resistor divider from the leader supply (V_X) to the TRACK/SS pin of the follower supply (V_{OUT}), as shown in Figure 49. During startup, V_{OUT} tracks V_X, according to the ratio set by the resistor divider in Equation 19:

$$\frac{V_X}{V_{OUT}} = \frac{R_A}{R_{TRACKA}} \times \frac{R_{TRACKA} + R_{TRACKB}}{R_A + R_B} \quad (19)$$

Set R_{TRACKA} = R_A and R_{TRACKB} = R_B for coincident tracking (V_{OUT} = V_X during startup).

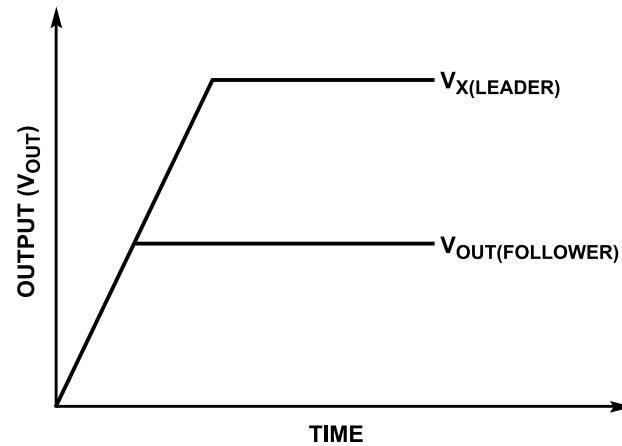


Figure 47. Coincident Tracking

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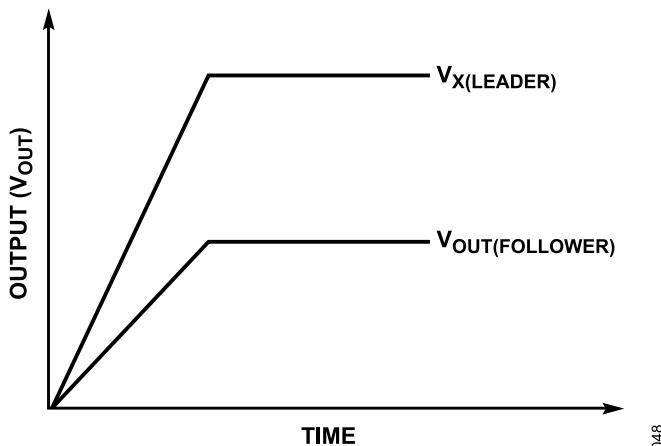


Figure 48. Ratiometric Tracking

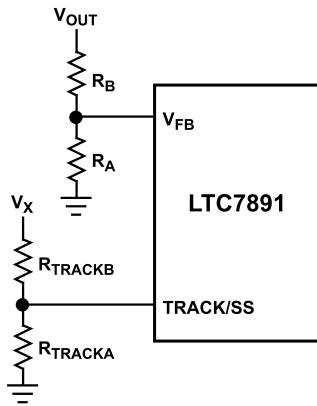


Figure 49. Using the TRACK/SS Pin for Tracking

INTV_{CC} REGULATORS (OPTI-DRIVE)

The LTC7891 features two separate internal LDO linear regulators that supply power at the INTV_{CC} pin from either the V_{IN} pin or the EXTV_{CC} pin, depending on the EXTV_{CC} pin voltage and connections to the DRVSET and DRVUV pins. The DRV_{CC} pin is the supply pin for the FET gate drivers and must be connected to the INTV_{CC} pin. The V_{IN} LDO regulator and the EXTV_{CC} LDO regulator regulate INTV_{CC} between 4 V and 5.5 V, depending on how the DRVSET pin is set. Each LDO regulator can provide a peak current of at least 100 mA.

Bypass the INTV_{CC} pin to GND with a minimum of 4.7 μ F ceramic capacitor, and place it as close as possible to the pin. It is recommended to place an additional 1 μ F ceramic capacitor next to the DRV_{CC} pin and GND pin to supply the high frequency transient currents required by the FET gate drivers.

The DRVSET pin programs the INTV_{CC} supply voltage, and the DRVUV pin selects the different INTV_{CC} UVLO and EXTV_{CC} switchover threshold voltages. **Table 6** summarizes the different DRVSET pin configurations along with the voltage settings that go with each configuration. **Table 7** summarizes the different DRVUV pin configurations and voltage settings. Tying the DRVSET pin

to INTV_{CC} programs INTV_{CC} to 5.5 V. Tying the DRVSET pin to GND programs INTV_{CC} to 5.0 V. Place a 43 k Ω to 100 k Ω resistor between DRVSET and GND to program the INTV_{CC} voltage between 4 V to 5.5 V, as shown in **Figure 50**.

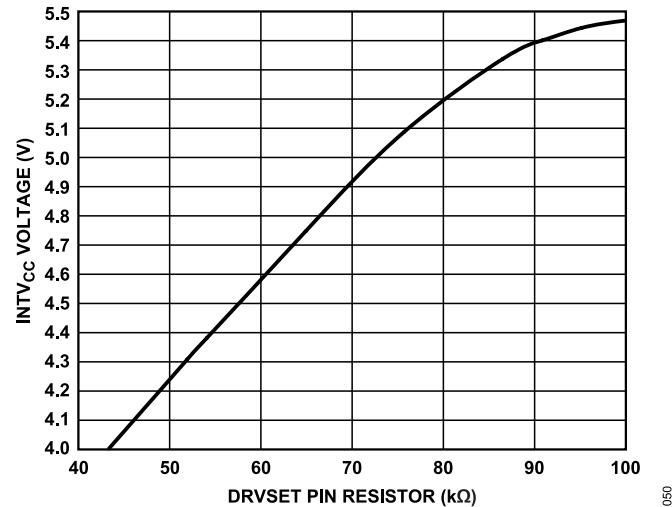
Figure 50. Relationship Between INTV_{CC} Voltage and Resistor Value at the DRVSET Pin

Table 6. DRVSET Pin Configurations and Voltage Settings

DRVSET Pin	INTV _{CC} Voltage (V)
GND	5.0
INTV _{CC}	5.5
Resistor to GND, 43 k Ω to 100 k Ω	4 to 5.5

Table 7. DRVUV Pin Configurations and Voltage Settings

DRVUV Pin	INTV _{CC} UVLO Rising and Falling Thresholds (V)	EXTV _{CC} Switchover Rising and Falling Thresholds (V)
GND	3.8 and 3.6	4.76 and 4.54
Floating	4.4 and 4.18	5.95 and 5.56
INTV _{CC}	5 and 4.75	5.95 and 5.56

High input voltage applications in which large FETs are driven at high frequencies can exceed the maximum junction temperature rating for the LTC7891. The INTV_{CC} current, which is dominated by the gate charge current, can be supplied by either the V_{IN} LDO regulator or the EXTV_{CC} LDO regulator. When the voltage on the EXTV_{CC} pin is less than its switchover threshold (4.76 V or 5.95 V, as determined by the DRVUV pin), the V_{IN} LDO regulator is enabled. In this case, power dissipation for the IC is equal to V_{IN} \times INTV_{CC} current (I_{INTVCC}). The gate charge current is dependent on the operating frequency, as discussed in the **Efficiency Considerations** section. To estimate the junction temperature, use the equation detailed in **Table 2**. For example, the LTC7891 INTV_{CC} current is limited to less than 39 mA from a 48 V supply when not using the EXTV_{CC} supply at an ambient temperature of 70°C, as shown in **Equation 20**:

$$T_J = 70^\circ\text{C} + (39\text{mA})(48\text{V})(43^\circ\text{C}/\text{W}) = 150^\circ\text{C} \quad (20)$$

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To prevent the maximum junction temperature from exceeding, check the input supply current while operating in continuous conduction mode (MODE = INTV_{CC}) at maximum V_{IN}.

When the voltage applied to EXTV_{CC} rises above its rising switch-over threshold, the V_{IN} LDO regulator turns off and the EXTV_{CC} LDO regulator enables. The EXTV_{CC} LDO regulator remains on as long as the voltage applied to EXTV_{CC} remains above its falling switchover threshold. The EXTV_{CC} LDO regulator attempts to regulate the INTV_{CC} voltage to the voltage as programmed by the DRVSET pin. Therefore, while EXTV_{CC} is less than 5 V, the LDO regulator is in dropout and the INTV_{CC} voltage is approximately equal to EXTV_{CC}. When EXTV_{CC} is greater than the programmed voltage (up to an absolute maximum of 30 V), INTV_{CC} is regulated to the programmed voltage. Using the EXTV_{CC} LDO regulator allows the FET driver and control power to be derived from the switching regulator output of the LTC7891 (4.7 V \leq V_{OUT} \leq 30 V) during normal operation, and from the V_{IN} LDO regulator when the output is out of regulation (for example, startup or short-circuit). If more current is required through the EXTV_{CC} LDO regulator than is specified, add an external Schottky diode between the EXTV_{CC} and INTV_{CC} pins. In this case, do not apply more than 6 V to the EXTV_{CC} pin.

Significant efficiency and thermal gains can be realized by powering INTV_{CC} from an output, because the V_{IN} current resulting from the driver and control currents is scaled by a factor of V_{OUT}/(V_{IN} \times efficiency). For 5 V to 30 V regulator outputs, connect the EXTV_{CC} pin to V_{OUT}. Tying the EXTV_{CC} pin to an 8.5 V supply reduces the junction temperature in [Equation 20](#) from 125°C to the results given by [Equation 21](#), as follows:

$$T_J = 70^\circ\text{C} + (39\text{mA})(8.5\text{V})(43^\circ\text{C}/\text{W}) = 84^\circ\text{C} \quad (21)$$

However, for 3.3 V and other low voltage outputs, additional circuitry is required to derive INTV_{CC} power from the output.

The following list summarizes the four possible connections for EXTV_{CC}:

1. EXTV_{CC} grounded. This connection causes the internal V_{IN} LDO regulator to power INTV_{CC}, resulting in an efficiency penalty of up to 10% or more at high input voltages.
2. EXTV_{CC} connected directly to the regulator output. This connection is the normal connection for an application with an output range of 5 V to 30 V and provides the highest efficiency.
3. EXTV_{CC} connected to an external supply. If an external supply is available, it can be used to power EXTV_{CC}, provided that it is compatible with the FET gate drive requirements. This supply can be higher or lower than V_{IN}. However, a lower EXTV_{CC} voltage results in higher efficiency.
4. EXTV_{CC} connected to an output derived boost or charge pump. For regulators where outputs are below 5 V, efficiency gains can still be realized by connecting EXTV_{CC} to an output derived voltage that is boosted to greater than the EXTV_{CC} switchover threshold.

TOPSIDE FET DRIVER SUPPLY (C_B)

An external bootstrap capacitor (C_B) connected to the BOOST pin supplies the gate drive voltage for the topside FET. C_B in [Figure 35](#) is charged through an internal switch from DRV_{CC} when the SW pin is low and the bottom FET is tuned on. The on resistance of the internal switch is approximately 7 Ω . To deliver more charge current to C_B under certain operating conditions, place an external Schottky diode between BSTV_{CC} and BOOST to bypass most of the internal switch resistance between DRV_{CC} and BOOST.

When the topside FET turns on, the driver places the C_B voltage across the gate source of the desired FET, which enhances the FET and turns on the topside switch. The switch node voltage, SW, rises to V_{IN} and the BOOST pin follows. With the topside FET on, the boost voltage is above the input supply: V_{BOOST} = V_{IN} + V_{INTVCC}. The value of C_B needs to be 100 times that of the total input capacitance of the topside FETs. For a typical application, a value of C_B = 0.1 μF is sufficient.

MINIMUM ON TIME CONSIDERATIONS

The minimum on time (t_{ON(MIN)}) is the smallest time duration that the LTC7891 is capable of turning on the top FET. t_{ON(MIN)} is determined by internal timing delays and the gate charge required to turn on the FET. Low duty cycle applications can approach this minimum on time limit. Take care to ensure the results in [Equation 22](#), as follows:

$$t_{ON(MIN)} < \frac{V_{OUT}}{V_{IN} \times f} \quad (22)$$

If the duty cycle falls below what can be accommodated by the minimum on time, the controller begins to skip cycles. The output voltage continues to be regulated, but the ripple voltage and current increases. The minimum on time for the LTC7891 is approximately 40 ns. However, as the peak sense voltage decreases, the minimum on time gradually increases up to about 60 ns. This change is of particular concern in forced continuous applications with low ripple current at light loads. If the duty cycle drops below the minimum on time limit in this situation, a significant amount of cycle skipping can occur with correspondingly larger current and voltage ripple.

FAULT CONDITIONS: CURRENT LIMIT AND FOLDBACK

The LTC7891 includes current foldback to reduce the load current when the output is shorted to GND. If the output voltage falls below 70% of its regulation point, the maximum sense voltage is progressively lowered from 100% to 40% of its maximum value. Under short-circuit conditions with low duty cycles, the LTC7891 begins cycle skipping to limit the short-circuit current. In this situation, the bottom FET dissipates most of the power, but less than in normal operation. The short-circuit ripple current ($\Delta I_{L(SC)}$) is determined by t_{ON(MIN)} \approx 40 ns, the input voltage, and the inductor value given by [Equation 23](#), as follows:

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$$\Delta I_{L(SC)} = t_{ON(MIN)} \times V_{IN}/L \quad (23)$$

The resulting average short-circuit current (I_{SC}) is given by [Equation 24](#), as follows:

$$I_{SC} = 40\% \times I_{LIM(MAX)} - \Delta I_{L(SC)}/2 \quad (24)$$

where $I_{LIM(MAX)}$ is the maximum peak inductor current.

FAULT CONDITIONS: OVERVOLTAGE PROTECTION

If the output voltage rises 10% above the set regulation point, the top FET turns off and the inductor current is not allowed to reverse until the overvoltage condition clears.

FAULT CONDITIONS: OVERTEMPERATURE PROTECTION

At higher temperatures, or in cases where the internal power dissipation causes excessive self heating (such as a short from $INTV_{CC}$ to GND), internal overtemperature shutdown circuitry shuts down the LTC7891. When the internal die temperature exceeds 180°C, the $INTV_{CC}$ LDO regulator and gate drivers disable. When the die cools to 160°C, the LTC7891 enables the $INTV_{CC}$ LDO regulator and resumes operation, beginning with a soft start startup. Avoid long-term overstress ($T_J > 125^\circ\text{C}$) because it can degrade the performance or shorten the life of the device.

PHASE-LOCKED LOOP AND FREQUENCY SYNCHRONIZATION

The LTC7891 has an internal PLL that allows the turn on of the top FET to be synchronized to the rising edge of an external clock signal applied to the PLLIN/SPREAD pin.

Rapid phase locking can be achieved by using the FREQ pin to set a free running frequency near the desired synchronization frequency. Before synchronization, the PLL is prebiased to the frequency set by the FREQ pin. Consequently, the PLL only needs to make minor adjustments to achieve phase lock and synchronization. Although it is not required, placing the free running frequency near the external clock frequency prevents the oscillator from passing through a large range of frequencies as the PLL locks.

When synchronized to an external clock, the LTC7891 operates in pulse skipping mode if it is selected by the MODE pin, or in forced continuous mode otherwise. The LTC7891 is guaranteed to synchronize to an external clock applied to the PLLIN/SPREAD pin that swings up to at least 2.2 V and down to 0.5 V or less. Note that the LTC7891 can only be synchronized to an external clock frequency within the range of 100 kHz to 3 MHz.

EFFICIENCY CONSIDERATIONS

The percent efficiency of a switching regulator is equal to the output power divided by the input power times 100%. Analyzing individual losses is useful for determining what is limiting the efficiency

and which change produces the most improvement. The percent efficiency can be expressed by [Equation 25](#), as follows:

$$\%Efficiency = 100\% - (L1 + L2 + L3 + \dots) \quad (25)$$

where $L1, L2, L3$, and so on, are the individual losses as a percentage of input power.

Although all dissipative elements in the circuit produce losses, four main sources usually account for most of the losses in LTC7891 circuits: $IC V_{IN}$ current, $INTV_{CC}$ regulator current, I^2R losses, and topside FET transition losses.

The V_{IN} current is the dc supply current given in [Table 1](#), which excludes FET driver and control currents. Other than at light loads in Burst Mode operation, V_{IN} current typically results in a small (<0.1%) loss.

The $INTV_{CC}$ current is the sum of the FET driver and control currents. The FET driver current results from switching the gate capacitance of the power FETs. Each time a FET gate is switched from low to high to low again, a packet of charge (dQ) moves from $INTV_{CC}$ to GND. The resulting dQ /time duration (dt) is a current out of $INTV_{CC}$ that is typically much larger than the control circuit current. In continuous mode, gate charge current ($I_{GATECHG}$) = SW frequency (f_{SW})($Q_T + Q_B$), where Q_T and Q_B are the gate charges of the top and bottom FETs.

Supplying $INTV_{CC}$ from an output derived source through $EXTV_{CC}$ scales the V_{IN} current required for the driver and control circuits by a factor of $V_{OUT}/(V_{IN} \times \text{efficiency})$. For example, in a 20 V to 5 V application, 10 mA of $INTV_{CC}$ current results in approximately 2.5 mA of V_{IN} current. This result reduces the mid-current loss from 10% or more (if the driver was powered directly from V_{IN}) to only a few percent.

I^2R losses are predicted from the dc resistances of the input fuse (if used), FET, inductor, current sense resistor, and input and output capacitor ESR. In continuous mode, the average output current flows through L and R_{SENSE} , but is chopped between the top and bottom FETs. If the two FETs have approximately the same $R_{DS(ON)}$, the resistance of one FET can be summed with the resistances of L, R_{SENSE} , and ESR to obtain the I^2R losses.

For example, if each $R_{DS(ON)} = 30\text{ m}\Omega$, $R_L = 50\text{ m}\Omega$, $R_{SENSE} = 10\text{ m}\Omega$, and $ESR = 40\text{ m}\Omega$ (the sum of both input and output capacitance losses), the total resistance is 130 mΩ. The resulting losses range from 3% to 13% as the output current increases from 1 A to 5 A for a 5 V output, or a 4% to 20% loss for a 3.3 V output. Efficiency varies as the inverse square of V_{OUT} for the same external components and output power level. The combined effects of increasingly lower output voltages and higher currents required by high performance digital systems is not doubling, but quadrupling the importance of loss terms in the switching regulator system.

Transition losses apply only to the top FETs and become significant only when operating at higher input voltages (typically 15 V or

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greater). Transition losses can be estimated using [Equation 26](#), as follows:

$$\text{Transition Loss} = 1.7(V_{IN})^2 \times I_{L(MAX)} \times C_{RSS} \times f_{SW} \quad (26)$$

where C_{RSS} is the reverse transfer capacitance.

Other hidden losses, such as copper trace and internal battery resistances, can account for an additional 5% to 10% efficiency degradation in portable systems. It is important to include these system level losses during the design phase. The internal battery and fuse resistance losses can be minimized by making sure that C_{IN} has adequate charge storage and low ESR at the switching frequency. A 25 W supply typically requires a minimum of 20 μ F to 40 μ F of capacitance with a maximum of 20 m Ω to 50 m Ω of ESR. Other losses, including inductor core losses, generally account for less than 2% total additional loss.

CHECKING TRANSIENT RESPONSE

To check the regulator loop response, look at the load current transient response. Switching regulators take several cycles to respond to a step in dc (resistive) load current. When a load step occurs, V_{OUT} shifts by an amount equal to $\Delta I_{LOAD} \times \text{ESR}$, where ESR is the effective series resistance of C_{OUT} . ΔI_{LOAD} also begins to charge or discharge C_{OUT} , generating the feedback error signal that forces the regulator to adapt to the current change and return V_{OUT} to its steady state value. During this recovery time, V_{OUT} can be monitored for excessive overshoot or ringing, which indicates a stability problem.

OPTI-LOOP compensation allows the transient response to be optimized over a wide range of output capacitance and ESR values. The availability of the ITH pin not only allows optimization of control loop behavior, but it also provides a dc-coupled and ac filtered closed-loop response test point. The dc step, rise time, and settling at this test point reflects the closed-loop response. Assuming a predominantly second order system, the phase margin and/or damping factor can be estimated using the percentage of overshoot seen at this pin. The bandwidth can also be estimated by examining the rise time at the pin. The ITH external components shown in [Figure 52](#), [Figure 54](#), [Figure 56](#), and [Figure 58](#) provide an adequate starting point for most applications.

The ITH series compensation resistor (R_C) to compensation capacitor (C_C) filter sets the dominant pole zero loop compensation. The values can be modified slightly (from 0.5 times to 2 times their initial values) to optimize transient response when the final PCB layout is done and the particular output capacitor type and value are determined. The output capacitors need to be selected because the various types and values determine the loop gain and phase. An output current pulse of 20% to 80% of the full load current, with a rise time of 1 μ s to 10 μ s, produces output voltage and ITH pin waveforms that give a sense of the overall loop stability without breaking the feedback loop.

Placing a power FET directly across from the output capacitor, and driving the gate with an appropriate signal generator, is a

practical way to produce a realistic load step condition. The initial output voltage step resulting from the step change in output current may not be within the bandwidth of the feedback loop. Therefore, this signal cannot be used to determine phase margin. For this reason, it is better to look at the ITH pin signal, which is in the feedback loop and is the filtered and compensated control loop response. The gain of the loop increases by increasing R_C , and the bandwidth of the loop increases by decreasing C_C . If R_C increases by the same factor that C_C decreases, the zero frequency is kept the same, keeping the phase shift the same in the most critical frequency range of the feedback loop. The output voltage settling behavior is related to the stability of the closed-loop system and demonstrates the actual overall supply performance.

A second, more severe transient is caused by switching in loads with large ($>1 \mu$ F) supply bypass capacitors. The discharged bypass capacitors are effectively put in parallel with C_{OUT} , causing a rapid drop in V_{OUT} . No regulator can alter its delivery of current quickly enough to prevent this sudden step change in output voltage, if the load switch resistance is low and it is driven quickly. If the ratio of C_{LOAD} to C_{OUT} is greater than 1:50, the switch rise time must be controlled so that the load rise time is limited to approximately $C_{LOAD} \times 25 \mu$ s/ μ F. Therefore, a 10 μ F capacitor requires a 250 μ s rise time, limiting the charging current to about 200 mA.

DESIGN EXAMPLE

As a design example, assume the nominal input voltage ($V_{IN(NOMINAL)}$) = 12 V, $V_{IN(MAX)} = 22$ V, $V_{OUT} = 3.3$ V, $I_{OUT} = 20$ A, and $f_{SW} = 1$ MHz.

Take the following steps to design an application circuit:

1. Set the operating frequency. The frequency is not one of the internal preset values. Therefore, a resistor from the FREQ pin to GND is required, with a value given by [Equation 27](#), as follows:

$$R_{FREQ} (\text{in } k\Omega) = \frac{37\text{MHz}}{1\text{MHz}} = 37k\Omega \quad (27)$$

2. Determine the inductor value. Initially, select a value based on an inductor ripple current of 30%. The inductor value can then be calculated using [Equation 28](#), as follows:

$$L = \frac{V_{OUT}}{f_{SW}(\Delta I_L)} \left(1 - \frac{V_{OUT}}{V_{IN(NOMINAL)}} \right) = 0.4\mu\text{H} \quad (28)$$

The highest value of the ripple current occurs at the maximum input voltage. In this case, the ripple at $V_{IN} = 22$ V is 35%.

3. Verify that the minimum on time of 40 ns is not violated. The minimum on time occurs at $V_{IN(MAX)}$, as shown in [Equation 29](#):

$$t_{ON(MIN)} = \frac{V_{OUT}}{V_{IN(MAX)}(f_{SW})} = 150\text{ns} \quad (29)$$

This time is sufficient to satisfy the minimum on time requirement. If the minimum on time is violated, the LTC7891 skips pulses at high input voltage, resulting in lower frequency opera-

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tion and higher inductor current ripple than desired. If undesirable, this behavior can be avoided by decreasing the frequency (with the inductor value accordingly adjusted) to avoid operation near the minimum on time.

4. Select the R_{SENSE} resistor value. The peak inductor current is the maximum dc output current plus half of the inductor ripple current, or $20\text{ A} \times (1 + 0.30/2) = 23\text{ A}$ in this case. The R_{SENSE} resistor value can then be calculated based on the minimum value for the maximum current sense threshold (45 mV for $ILIM = \text{float}$), given by [Equation 30](#), as follows:

$$R_{SENSE} \leq \frac{45\text{mV}}{23\text{A}} \cong 2\text{m}\Omega \quad (30)$$

To allow for additional margin, a lower value R_{SENSE} can be used (for example, 1.8 mΩ). However, be sure that the inductor saturation current has sufficient margin above $V_{SENSE(MAX)}/R_{SENSE}$, where the maximum value of 55 mV is used for $V_{SENSE(MAX)}$.

5. Select the feedback resistors. If light load efficiency is required, high value feedback resistors can be used to minimize the current due to the feedback divider. However, in most applications, a feedback divider current in the range of 10 μA to 100 μA or more is acceptable. For a 50 μA feedback divider current, $R_A = 0.8\text{ V}/50\text{ }\mu\text{A} = 16\text{ k}\Omega$. R_B can then be calculated as $R_B = R_A(3.3\text{ V}/0.8\text{ V} - 1) = 50\text{ k}\Omega$.
6. Select the FETs. The best way to evaluate FET performance in a particular application is to build and test the circuit on the bench, facilitated by an LTC7891 evaluation board. However, an educated guess about the application is helpful to initially select FETs. Because this is a high current, low voltage application, I^2R losses likely dominate over transition losses for the top FET. Therefore, choose a FET with lower $R_{DS(ON)}$ as opposed to lower gate charge to minimize the combined loss terms. The bottom FET does not experience transition losses, and its power loss is generally dominated by I^2R losses. For this reason, the bottom FET is typically chosen to be of lower $R_{DS(ON)}$ and higher gate charge than the top FET.

Due to the high current in this application, two FETs may be needed in parallel to more evenly balance the dissipated power

and to lower the $R_{DS(ON)}$. When using silicon MOSFETs, be sure to select logic level threshold MOSFETs, because the gate drive voltage is limited to 5.5 V ($INTV_{CC}$).

7. Select the input and output capacitors. C_{IN} is chosen for an rms current rating of at least 10 A ($I_{OUT}/2$, with margin) at temperature. C_{OUT} is chosen with an ESR of 3 mΩ for low output ripple. Multiple capacitors connected in parallel may be required to reduce the ESR to this level. The output ripple in continuous mode is highest at the maximum input voltage. The output voltage ripple ($V_{ORIPPLE}$) due to ESR is approximately given by [Equation 31](#), as follows:

$$V_{ORIPPLE} = ESR \times \Delta I_L = 3\text{m}\Omega \times 6\text{A} = 18\text{mVp-p} \quad (31)$$

On the 3.3 V output, 18 mVp-p is equal to 0.55% of the peak-to-peak voltage ripple.

8. Determine the bias supply components. Because the regulated output is not greater than the $EXTV_{CC}$ switchover threshold, it cannot be used to bias $INTV_{CC}$. However, if another 5 V supply is available, connect that supply to $EXTV_{CC}$ to improve the efficiency. For a 6.7 ms soft start, select a 0.1 μF capacitor for the TRACK/SS pin. As a first pass estimate for the bias components, select the $INTV_{CC}$ capacitance ($C_{INTVCC} = 4.7\text{ }\mu\text{F}$) and $C_B = 0.1\text{ }\mu\text{F}$.
9. Determine and set application specific parameters. Set the MODE pin based on the trade-off of light load efficiency and constant frequency operation. Set the PLLIN/SPREAD pin based on whether a fixed, spread spectrum, or phase-locked frequency is desired. The RUN pin can be used to control the minimum input voltage for regulator operation, or it can be tied to V_{IN} for always on operation. Use ITH compensation components from the typical applications as a first guess, check the transient response for stability, and modify as necessary.

PCB LAYOUT CHECKLIST

[Figure 51](#) shows the current waveforms present in the various branches of the synchronous regulators operating in the continuous mode.

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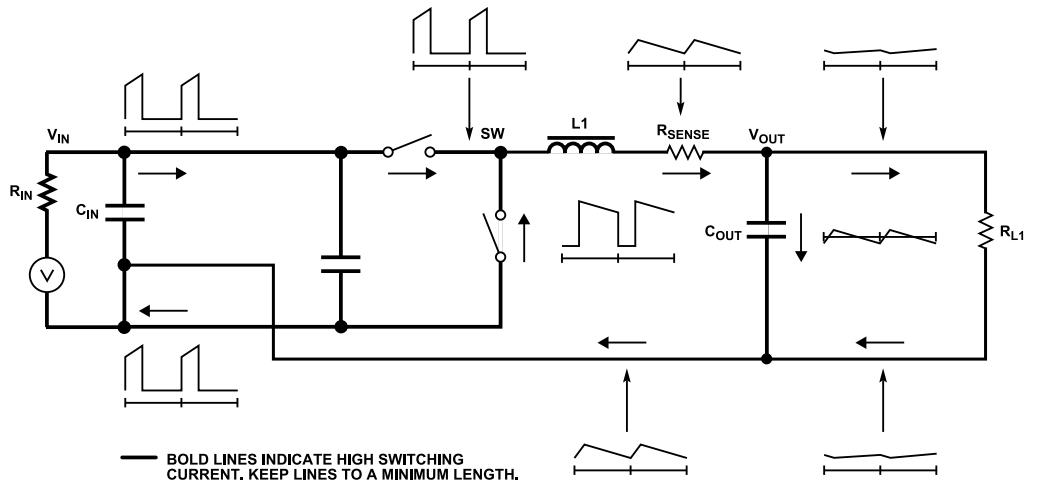


Figure 51. Branch Current Waveform

When laying out the PCB, use the following checklist to ensure proper operation of the IC.

1. Route the BGUP and BGDN traces together and connect them as close as possible to the bottom FET gate. If using gate resistors, connect the resistor connections to the FET gate as close as possible to the FET. Connecting BGUP and BGDN further away from the bottom FET gate can cause inaccuracies in the dead time control circuit of the LTC7891. Route the TGUP and TGDN traces together and connect them as close as possible to the top FET gate.
2. The combined IC GND pin and the GND return of C_{INTVCC} must return to the combined C_{OUT} negative terminals. The path formed by the top N-channel FET and the C_{IN} capacitor must have short leads and PCB trace lengths. Connect the output capacitor negative terminals as close as possible to the negative terminals of the input capacitor by placing the capacitors next to each other and away from the loop.
3. Connect the LTC7891 V_{FB} pin resistive dividers to the positive terminals of C_{OUT} and the signal GND. Place the divider close to the V_{FB} pin to minimize noise coupling into the sensitive V_{FB} node. The feedback resistor connections must not be along the high current input feeds from the input capacitors.
4. Route the $SENSE^-$ and $SENSE^+$ leads together with minimum PCB trace spacing. Route these traces away from the high frequency switching nodes on an inner layer, if possible. The filter capacitor between $SENSE^+$ and $SENSE^-$ must be as close as possible to the IC. Ensure accurate current sensing with Kelvin connections at the sense resistor.
5. Connect the $INTV_{CC}$ decoupling capacitor close to the IC, between the $INTV_{CC}$ and the power GND pin. This capacitor carries the current peaks of the FET drivers. Place an additional 1 μ F ceramic capacitor next to the DRV_{CC} and GND pins to help improve noise performance.
6. Keep the switching node (SW), top gate nodes (TGUP and TGDN), and boost node (BOOST) away from sensitive small

signal nodes, especially from the voltage and current sensing feedback pins. All of these nodes have large and fast moving signals. Therefore, keep the nodes on the output side of the LTC7891 and ensure they occupy the minimum PCB trace area.

7. Use a modified star ground technique: a low impedance, large copper area central grounding point on the same side of the PCB as the input and output capacitors, with tie ins for the bottom of the $INTV_{CC}$ decoupling capacitor, the bottom of the voltage feedback resistive divider, and the GND pin of the IC.

PCB LAYOUT DEBUGGING

Use a dc to 50 MHz current probe to monitor the current in the inductor while testing the circuit. Monitor the output switching node (the SW pin) to synchronize the oscilloscope to the internal oscillator and probe the actual output voltage as well. Check for proper performance over the operating voltage and current range expected in the application. The frequency of operation is maintained over the input voltage range down to dropout and until the output load drops below the low current operation threshold, typically 25% of the maximum designed current level in Burst Mode operation.

The duty cycle percentage is maintained from cycle to cycle in a well designed, low noise PCB implementation. Variation in the duty cycle at a subharmonic rate can suggest noise pickup at the current or voltage sensing inputs or inadequate loop compensation. Overcompensation of the loop can be used to tame an improper PCB layout if regulator bandwidth optimization is not required.

Reduce V_{IN} from its nominal level to verify operation of the regulator in dropout. Check the operation of the undervoltage lockout circuit by further lowering V_{IN} while monitoring the outputs to verify operation. Investigate whether any problems exist only at higher output currents or only at higher input voltages. If problems coincide with high input voltages and low output currents, look for capacitive coupling between the BOOST, SW, TGxx, and possibly BGxx connections and the sensitive voltage and current pins. Place the capacitor across the current sensing pins next to the pins of the

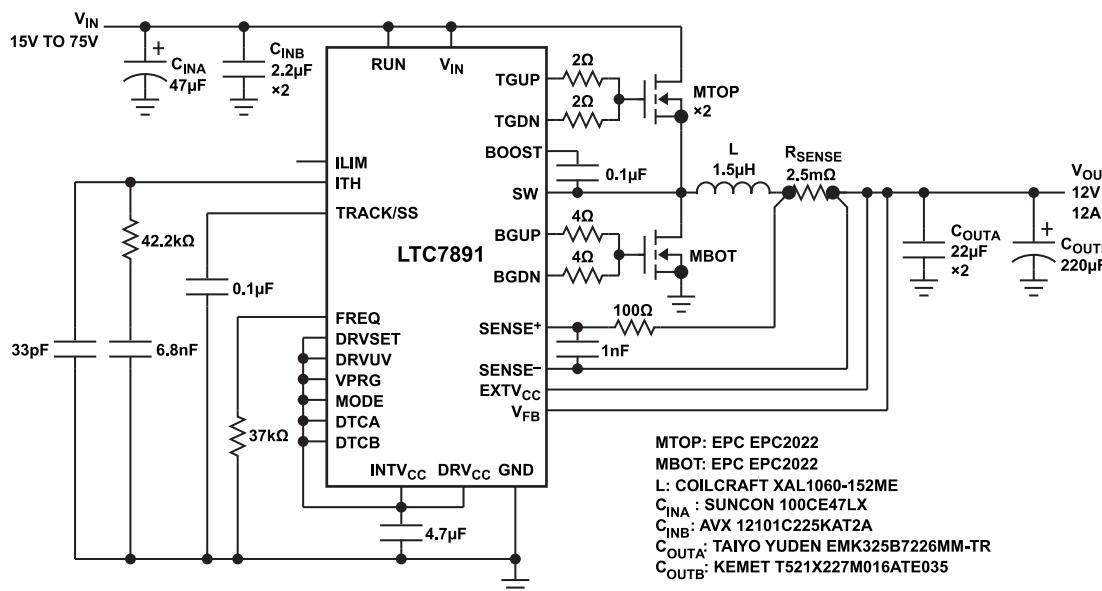
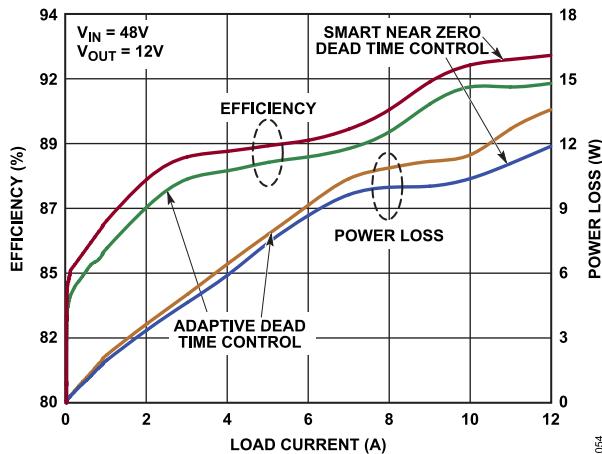
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IC. This capacitor helps to minimize the effects of differential noise injection due to high frequency capacitive coupling. If problems are encountered with high current output loading at lower input voltages, look for inductive coupling between C_{IN} , the top FET, and the bottom FET components to the sensitive current and voltage sensing traces. In addition, investigate the common GND path voltage pickup between these components and the GND pin of the IC.

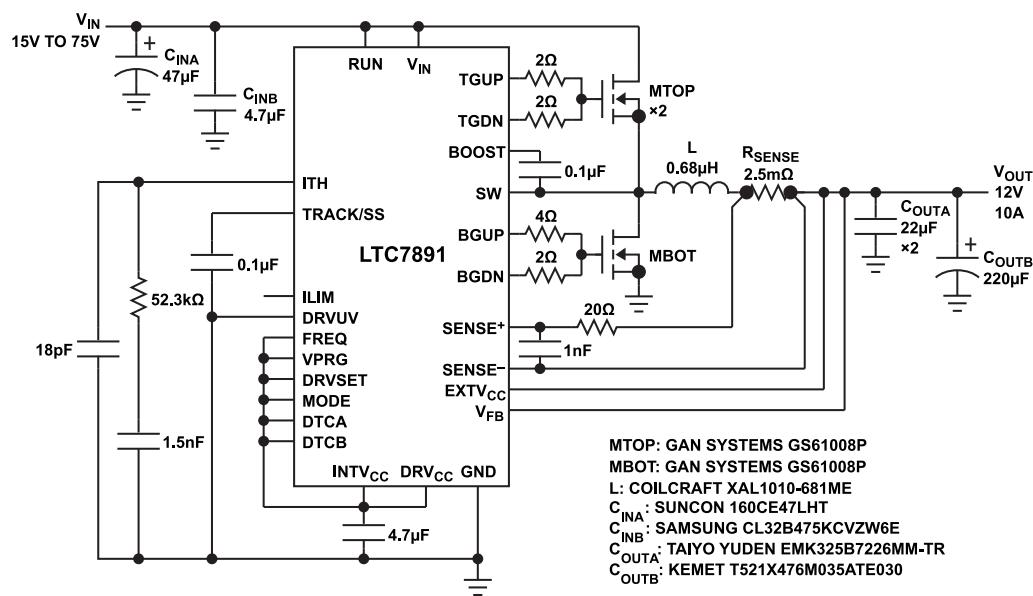
A problem that can be missed in an otherwise properly working switching regulator, results when the current sensing leads are hooked up backwards. The output voltage under this improper hookup is maintained, but the advantages of current mode control are not realized. Compensation of the voltage loop is more sensitive to component selection. This behavior can be investigated by temporarily shorting out the current sensing resistor. The regulator maintains control of the output voltage.

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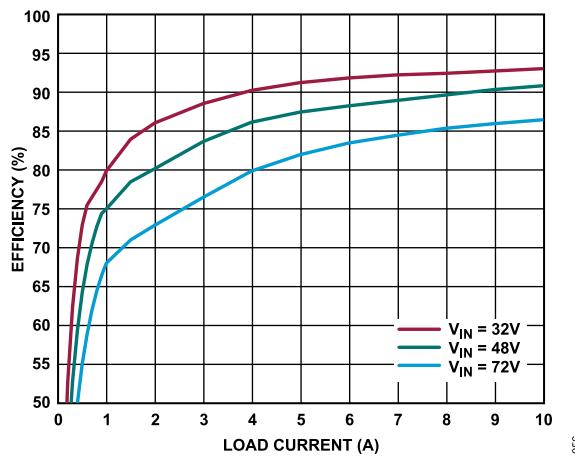
TYPICAL APPLICATIONS

Figure 52. High Efficiency, 12 V_{OUT}, 12 A, 1 MHz, Step-Down Regulator Using GaN FETsFigure 53. V_{OUT} Efficiency and Power Loss vs. Load Current for Figure 52

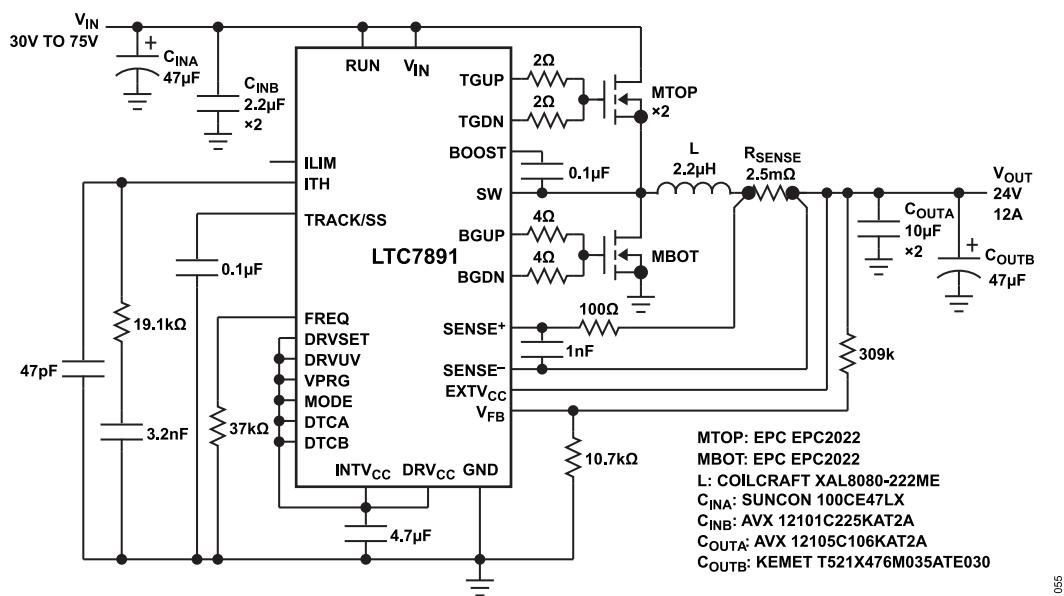
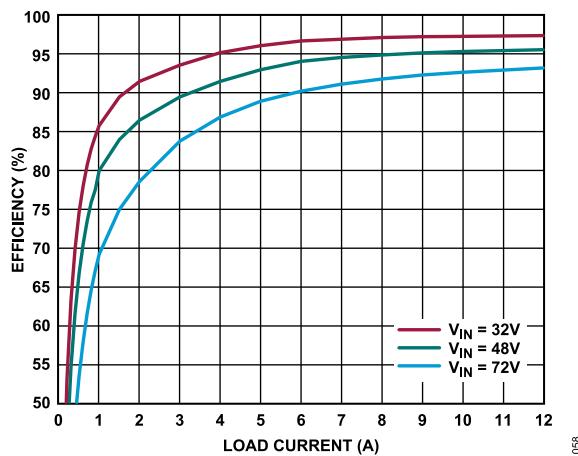
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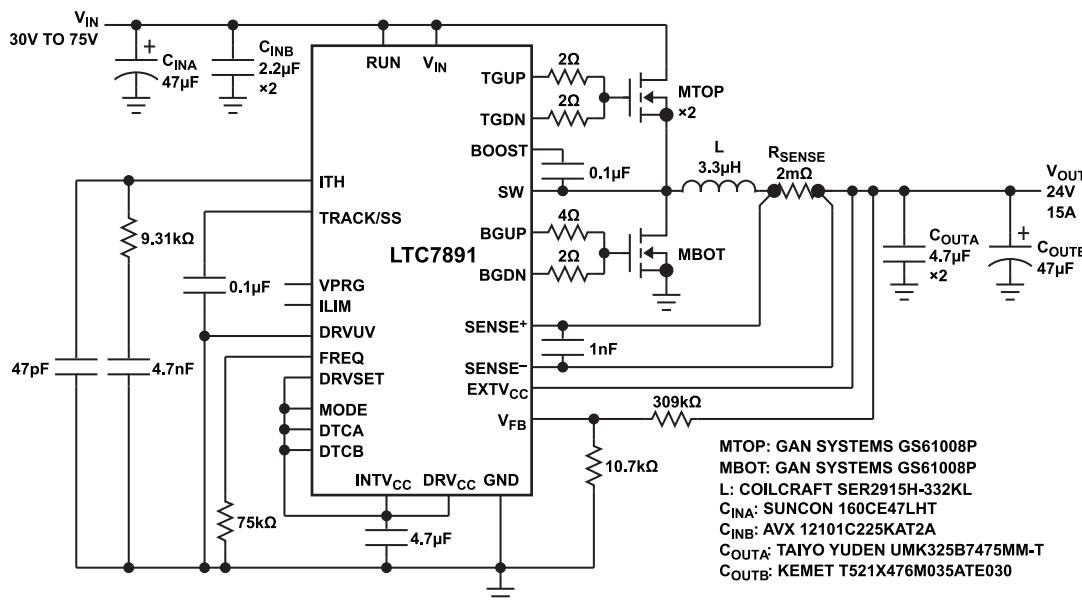
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Figure 54. High Efficiency 12 V_{OUT}, 10 A, 2 MHz, Step-Down Regulator Using GaN FETsFigure 55. V_{OUT} Efficiency vs. Load Current for Figure 54

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Figure 56. High Efficiency, 24 V_{OUT}, 1 MHz, Step-Down Regulator Using GaN FETsFigure 57. V_{OUT} Efficiency vs. Load Current for Figure 56

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RELATED PRODUCTS

Table 8. Related Products

Model	Description	Comments
LTC7803	40 V, low I_Q , 3 MHz, synchronous step-down controller with spread spectrum	PLL fixed frequency of 100 kHz to 3 MHz, $4.5 V \leq V_{IN} \leq 40 V$, $I_Q = 12 \mu A$, $0.8 V \leq V_{OUT} \leq 40 V$, 3 mm × 3 mm, 16-lead quad flat no lead (QFN) package, 16-lead mini small outline package (MSOP)
LTC7805	40 V, dual, low I_Q , two phase, synchronous step-down controller with 100% duty cycle	PLL fixed frequency of 100 kHz to 3 MHz, $4.5 V \leq V_{IN} \leq 40 V$, $I_Q = 14 \mu A$, V_{OUT} up to 40 V, 4 mm × 5 mm, 28-lead QFN package
LTC7802	40 V, dual, low I_Q , 3 MHz, two phase, synchronous step-down controller with spread spectrum	$4.5 V \leq V_{IN} \leq 40 V$, V_{OUT} up to 40 V, $I_Q = 12 \mu A$, PLL fixed frequency of 100 kHz to 3 MHz, 4 mm × 5 mm, 28-lead QFN package
LTC7800	60 V, low I_Q , high frequency, synchronous step-down controller	$4 V \leq V_{IN} \leq 60 V$, $0.8 V \leq V_{OUT} \leq 24 V$, $I_Q = 50 \mu A$, PLL fixed frequency of 320 kHz to 2.25 MHz, 3 mm × 4 mm, 20-lead QFN package
LTC7804	40 V, low I_Q , 3 MHz, synchronous boost controller, 100% duty cycle capable	$4.5 V$ (down to 1 V after startup) $\leq V_{IN} \leq 40 V$, V_{OUT} up to 40 V, $I_Q = 14 \mu A$, PLL fixed frequency of 100 kHz to 3 MHz, 3 mm × 3 mm, 16-lead QFN package, 16-lead MSOP
LTC3866	38 V, synchronous step-down controller with sub mΩ DCR sensing and differential output sense	$4.5 V \leq V_{IN} \leq 38 V$, $0.6 V \leq V_{OUT} \leq 3.5 V$, PLL fixed frequency of 250 kHz to 770 kHz, 4 mm × 4 mm, 24-lead QFN package, 24-lead thin shrink small outline package (TSSOP)
LTC3833	38 V, synchronous step-down controller with differential output voltage sensing	$4.5 V \leq V_{IN} \leq 38 V$, $0.6 V \leq V_{OUT} \leq 5.5 V$, PLL fixed frequency of 200 kHz to 2 MHz, 3 mm × 4 mm, 20-lead QFN package, 20-lead TSSOP
LTC7801	150 V, low I_Q , synchronous step-down dc-to-dc controller	$4.5 V \leq V_{IN} \leq 140 V$, $150 V_{PK}$, $0.8 V \leq V_{OUT} \leq 60 V$, $I_Q = 40 \mu A$, PLL fixed frequency of 50 kHz to 900 kHz, 4 mm × 5 mm, 24-lead QFN package, 24-lead TSSOP

OUTLINE DIMENSIONS

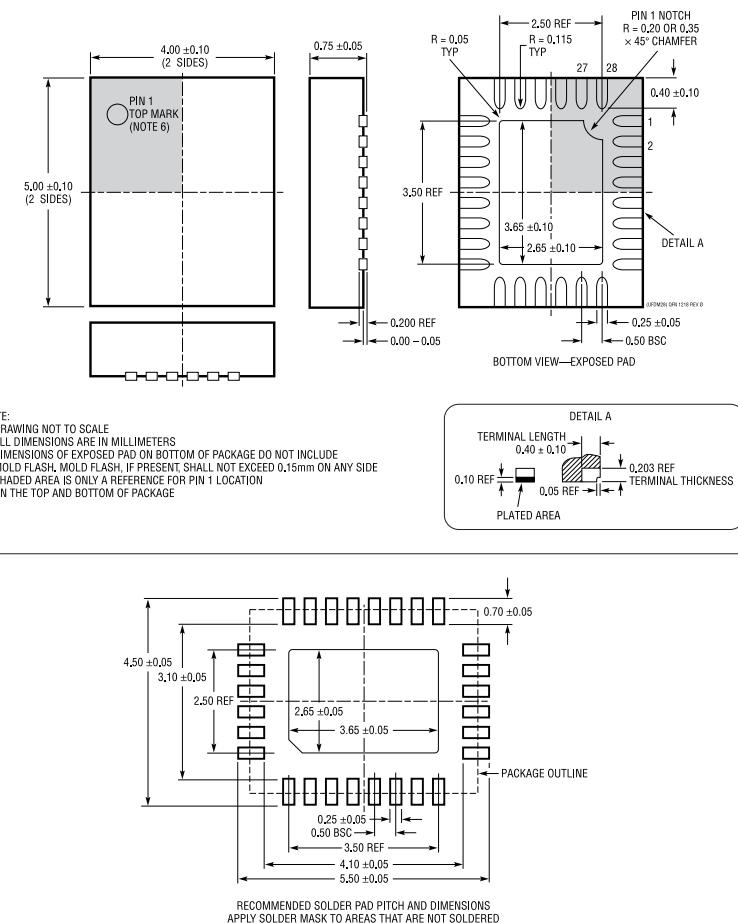


Figure 59. 28-Lead Plastic Side Wettable QFN

4 mm x 5 mm

(05-08-1682)

Dimensions shown in millimeters

Updated: March 16, 2022

ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Packing Quantity	Package Option
LTC7891RUFDM#PBF	-40°C to +150°C	28-Lead QFN (4mm x 5mm, Plastic Side Wettable)	Tube, 73	05-08-1682
LTC7891RUFDM#TRPBF	-40°C to +150°C	28-Lead QFN (4mm x 5mm, Plastic Side Wettable)	Reel, 2500	05-08-1682

¹ All models are RoHS compliant parts.

EVALUATION BOARDS

Model ¹	Description
DC2995A	Evaluation Board

¹ The DC2995A is an RoHS compliant part.

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